



photon sensor

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for CAL school at CCAST

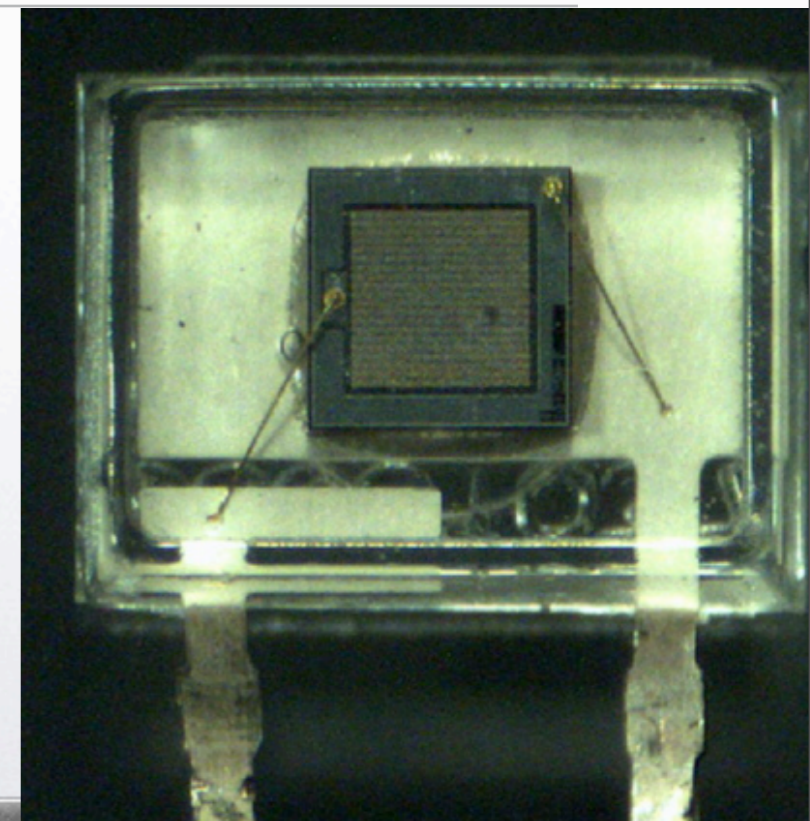
MPPPC in general

Basic performances

cross talk/after pulse

saturation effect

statistical experience



MPPPC

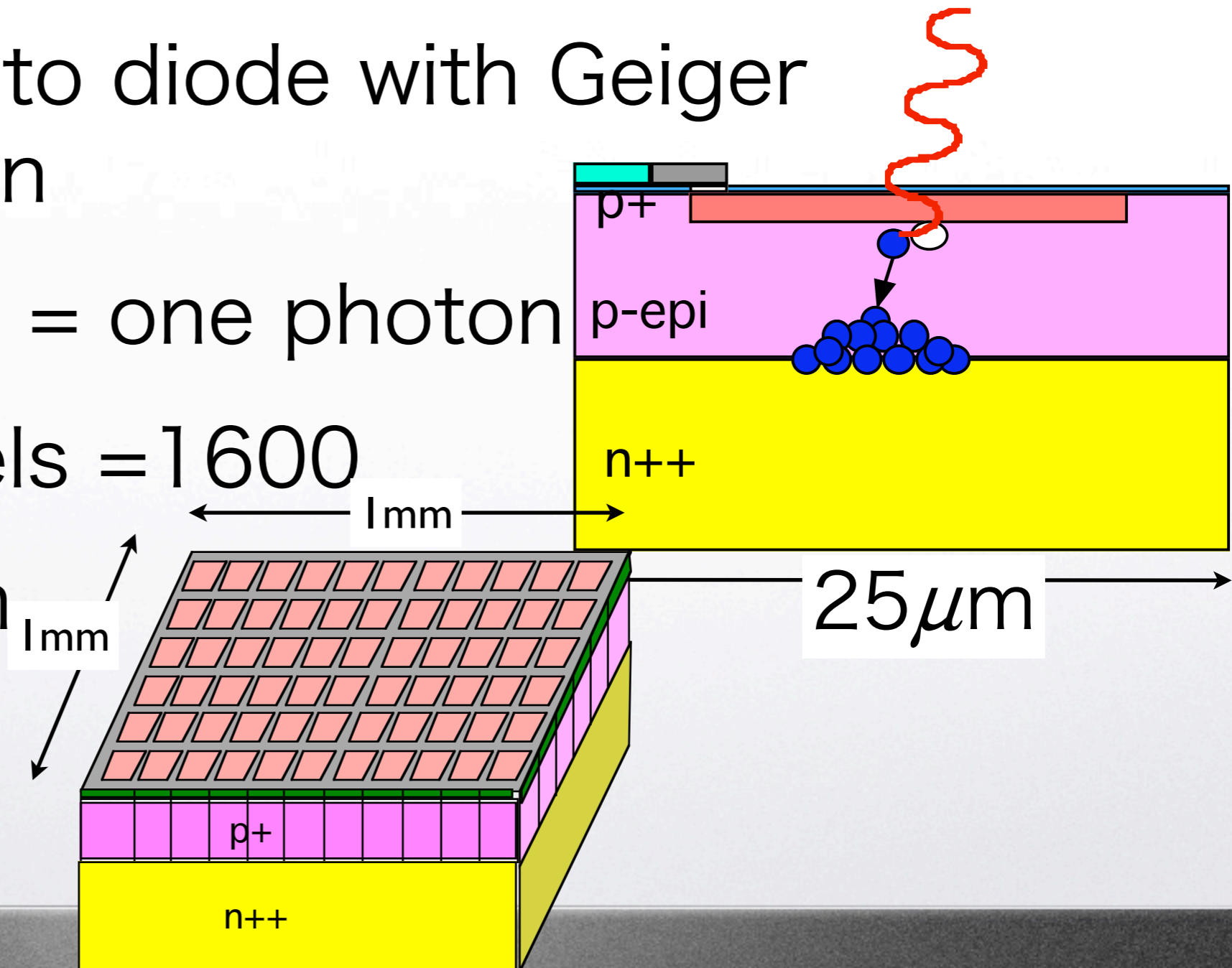
Multi Pixel Photon Counter

- Silicon photo sensor
- Avalanche photo diode with Geiger Mode operation

• one pixel firing = one photon

• with many pixels = 1600

• in 1mm x 1mm

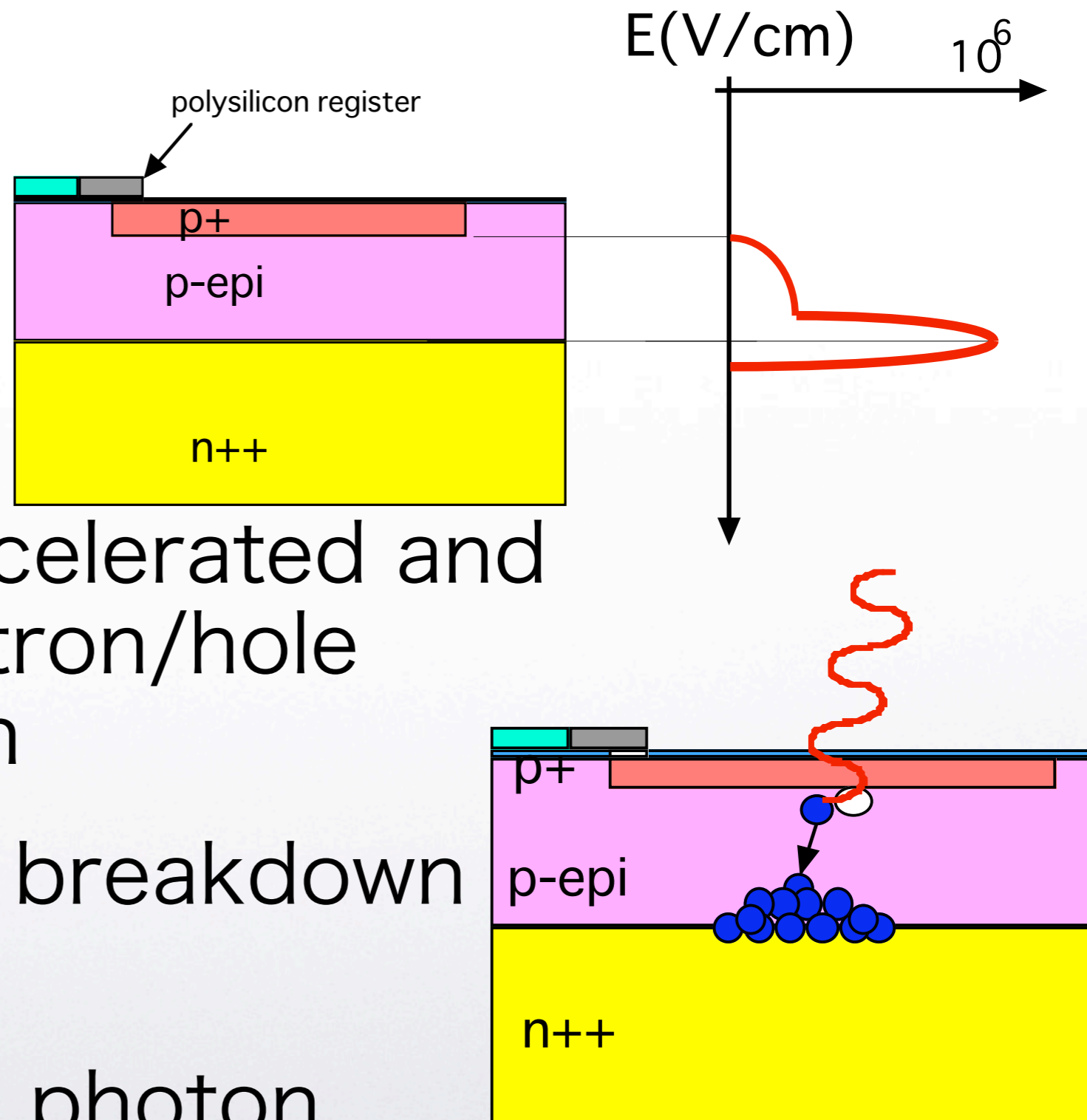




Geiger Mode



- strong electric field
- with very thin area in a pixel
- electron will be accelerated and induce other electron/hole pair : multiplication
- V threshold called breakdown voltage
- same charge for a photon

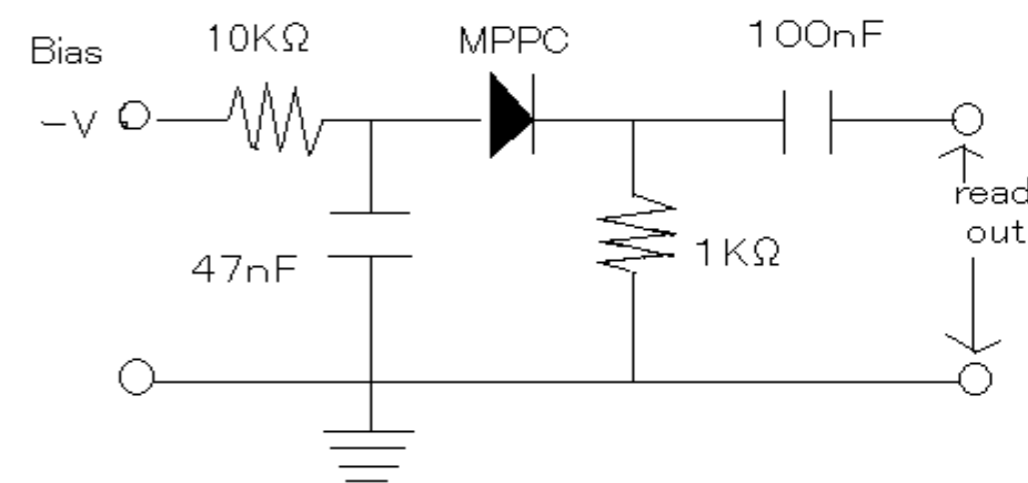
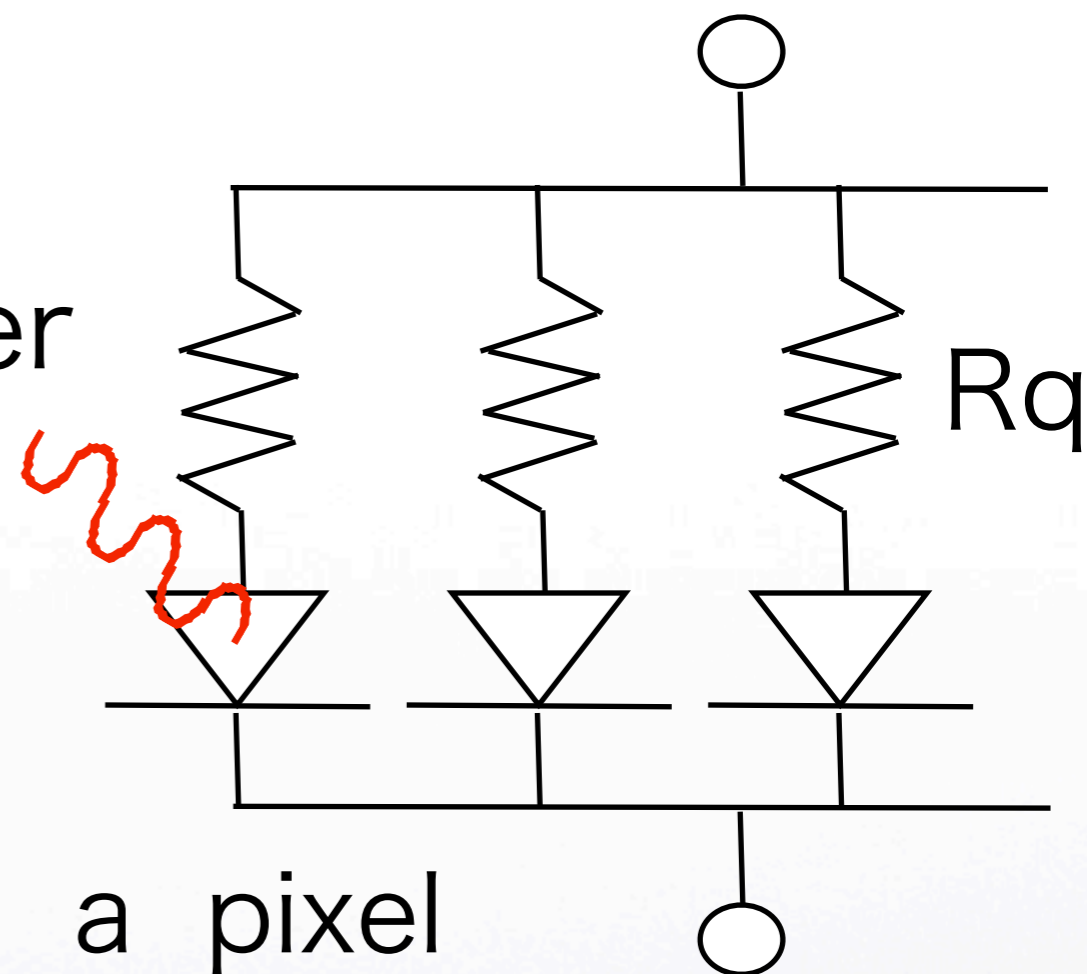




circuit

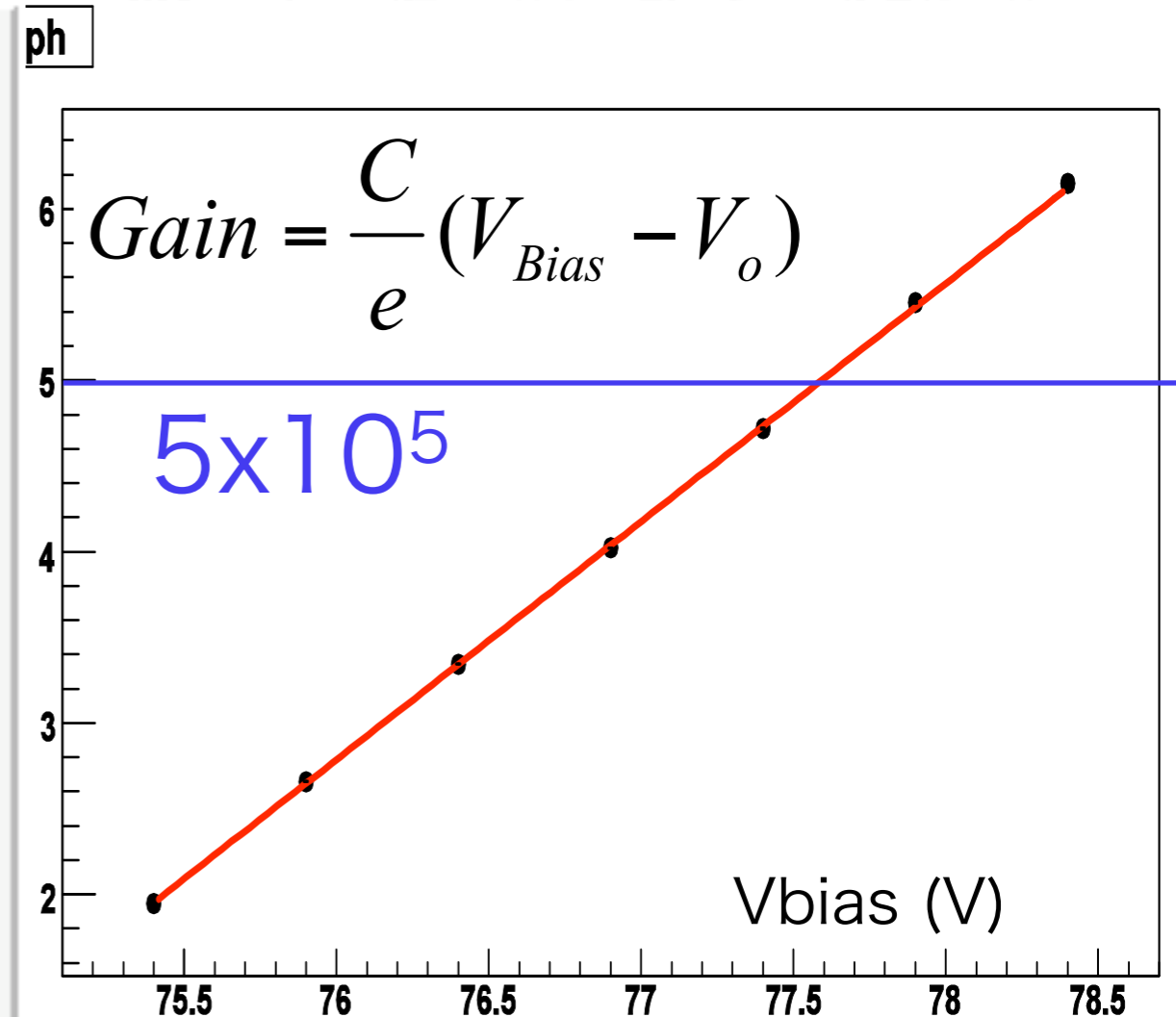
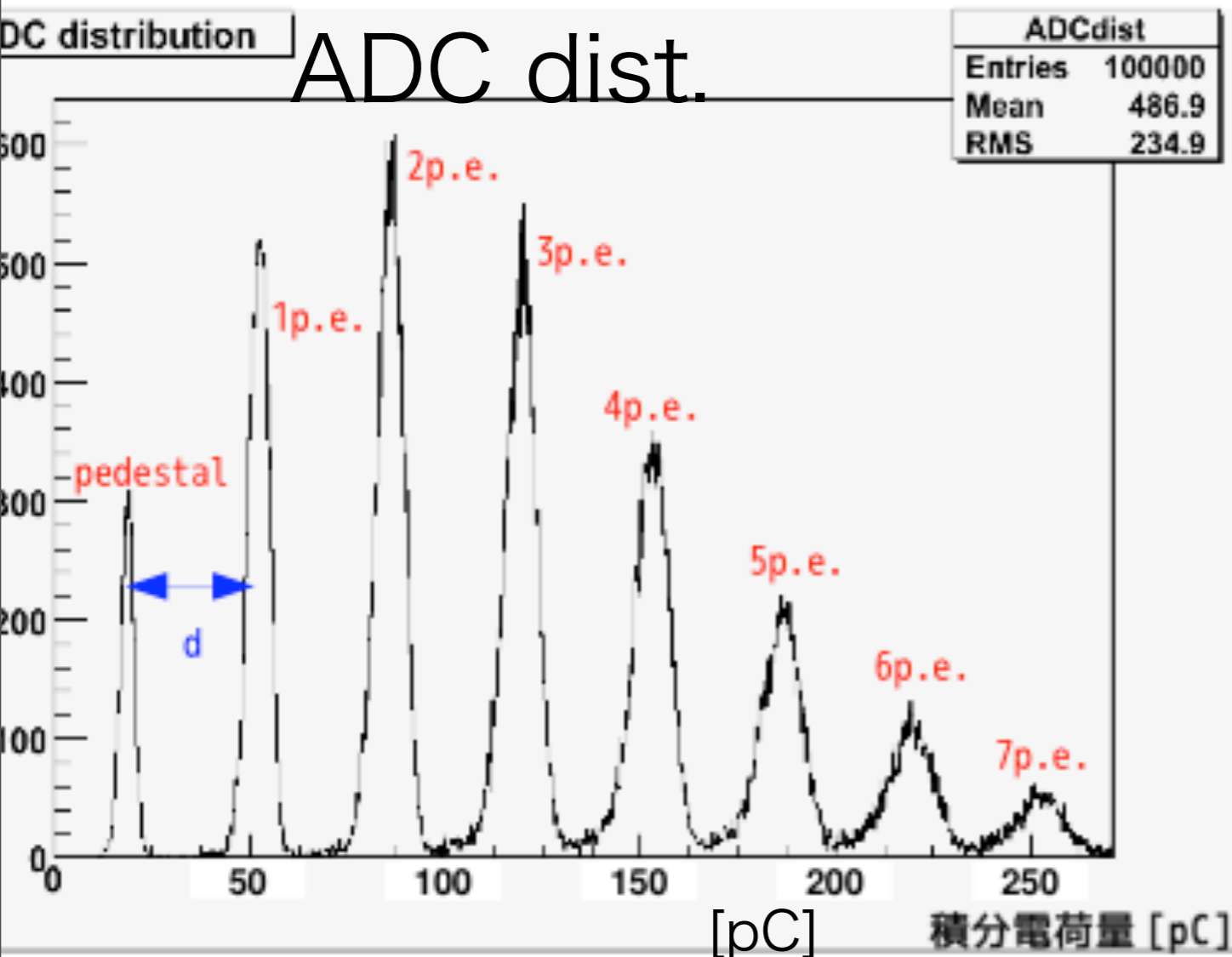


- equivalent circuit
- there is quenching register
- $R_q \sim 500k\Omega$
- capacitance $\sim 0.02pF$
- time const. 10ns
- like a condensor/capacitor
- triggered by a photon



Gain

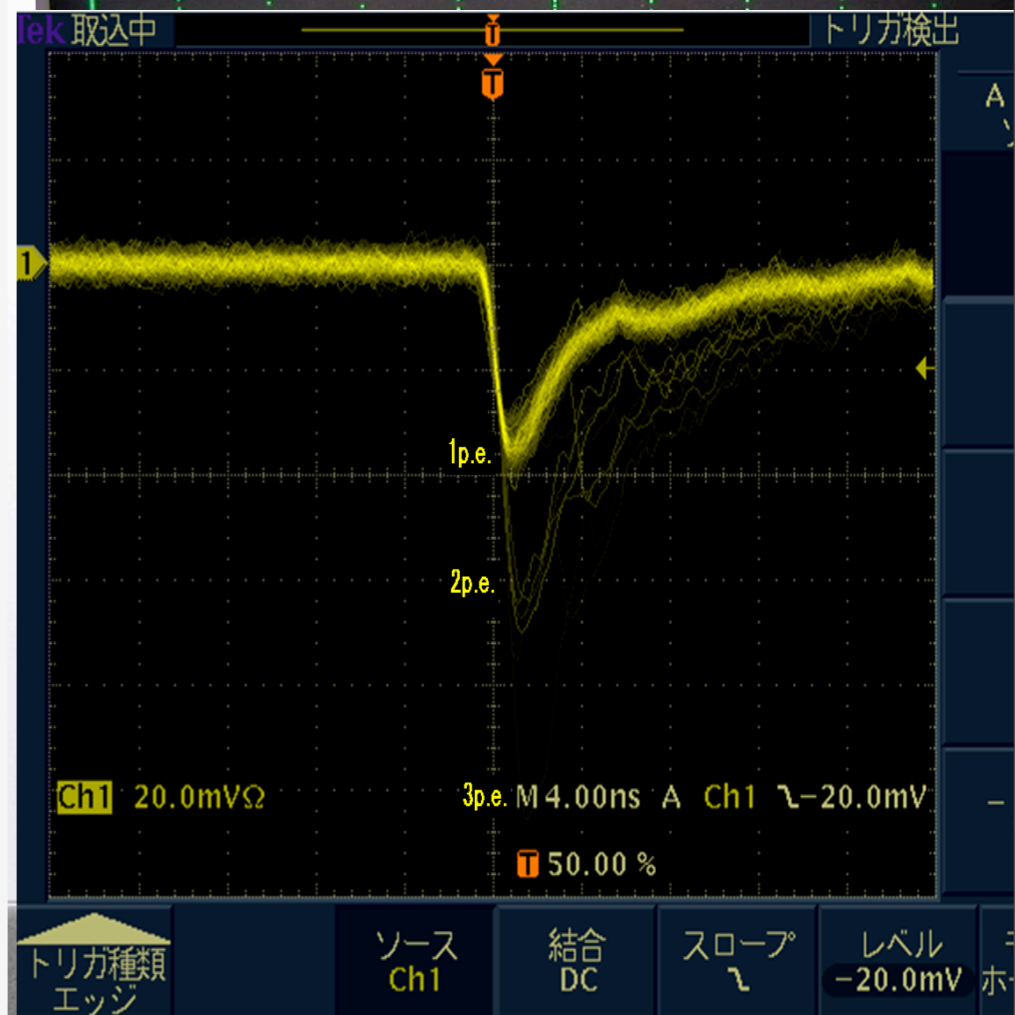
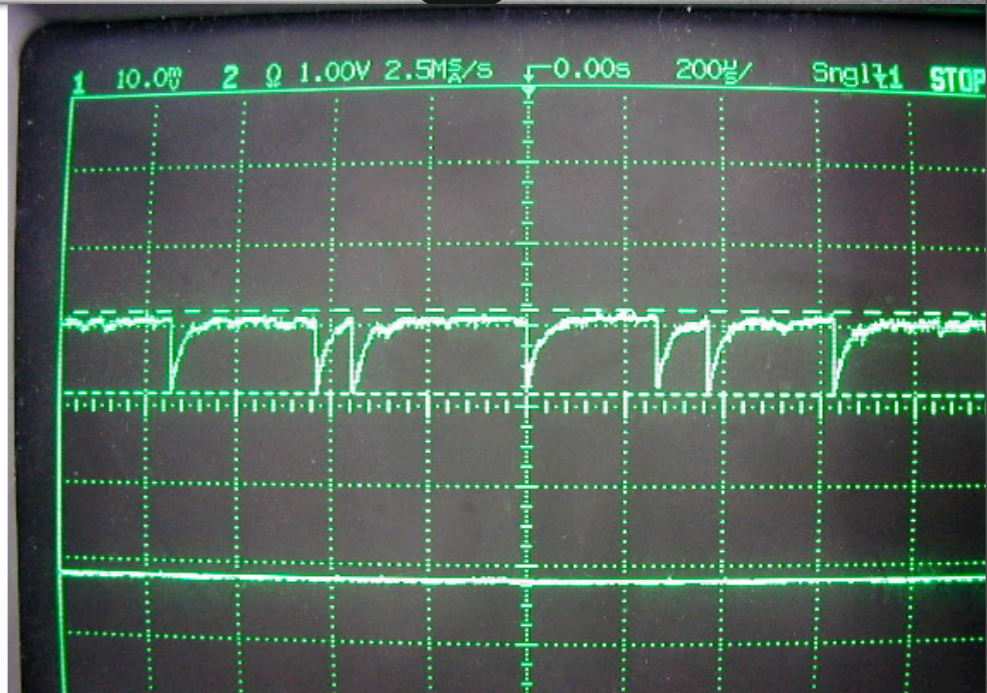
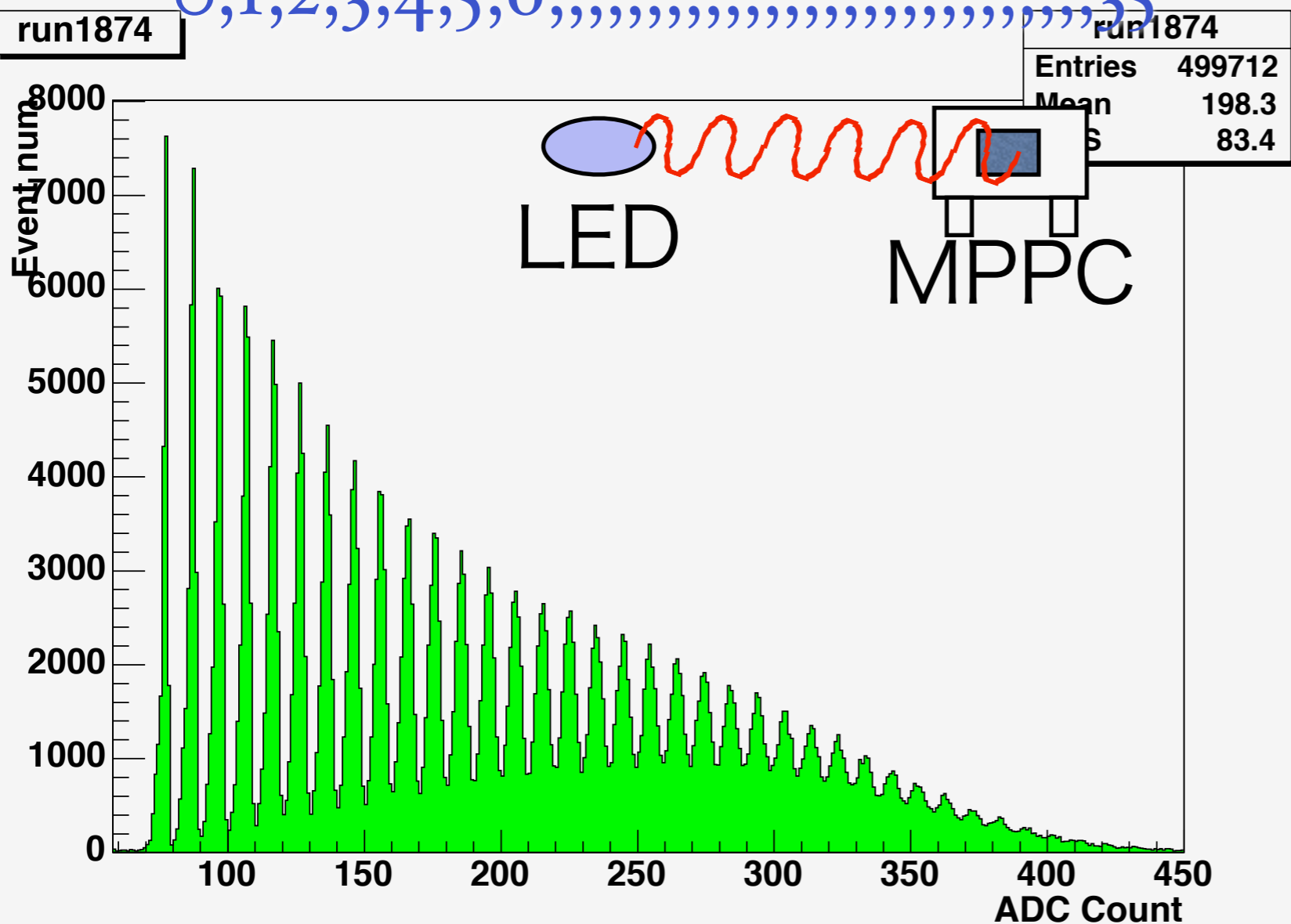
- Gain $\sim 10^{5\sim6}$ with Geiger mode
- Gain $\sim (V_{\text{bias}} - V_{\text{breakdown}})C/e$
- photon counting capability



photon counting

- uniform response for all pixel
- # of photons ~ # of pixels

0, 1, 2, 3, 4, 5, 6,, 35

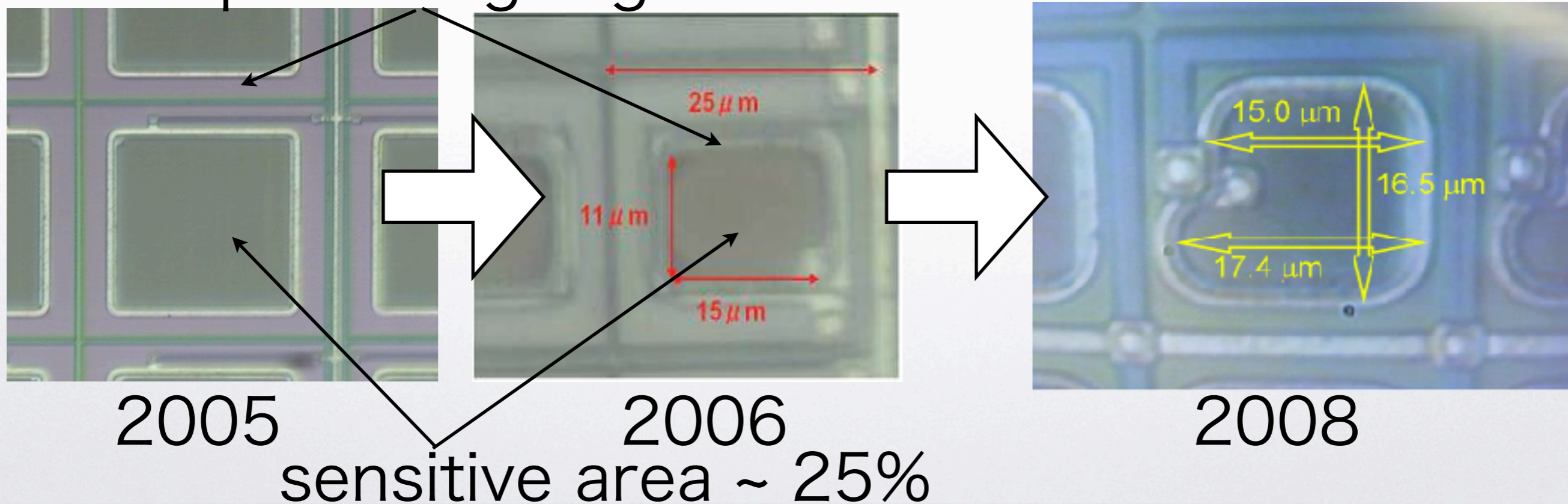




development with HPK

- Hamamatsu photonics company
- responsible MPPC prod.

quenching register

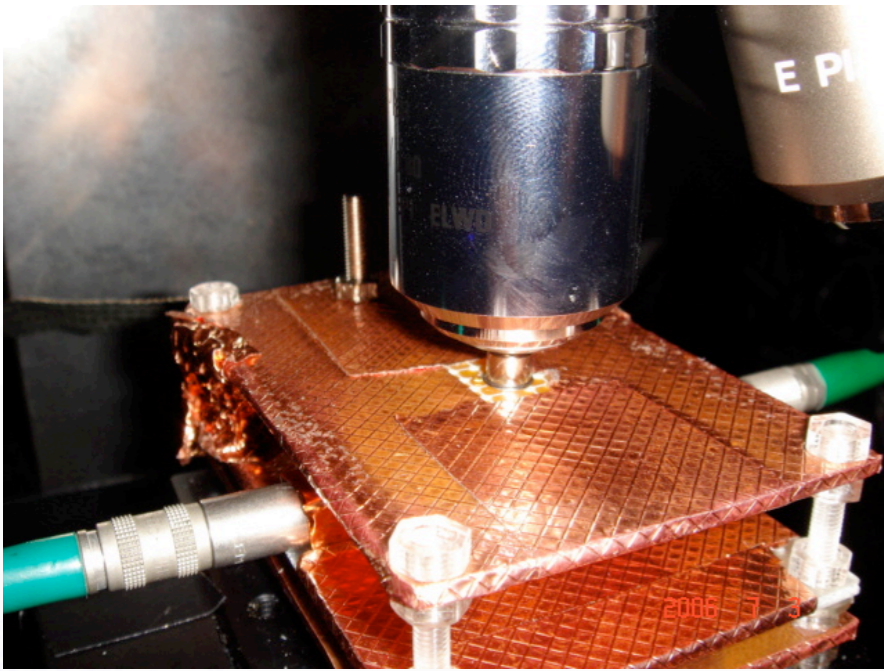




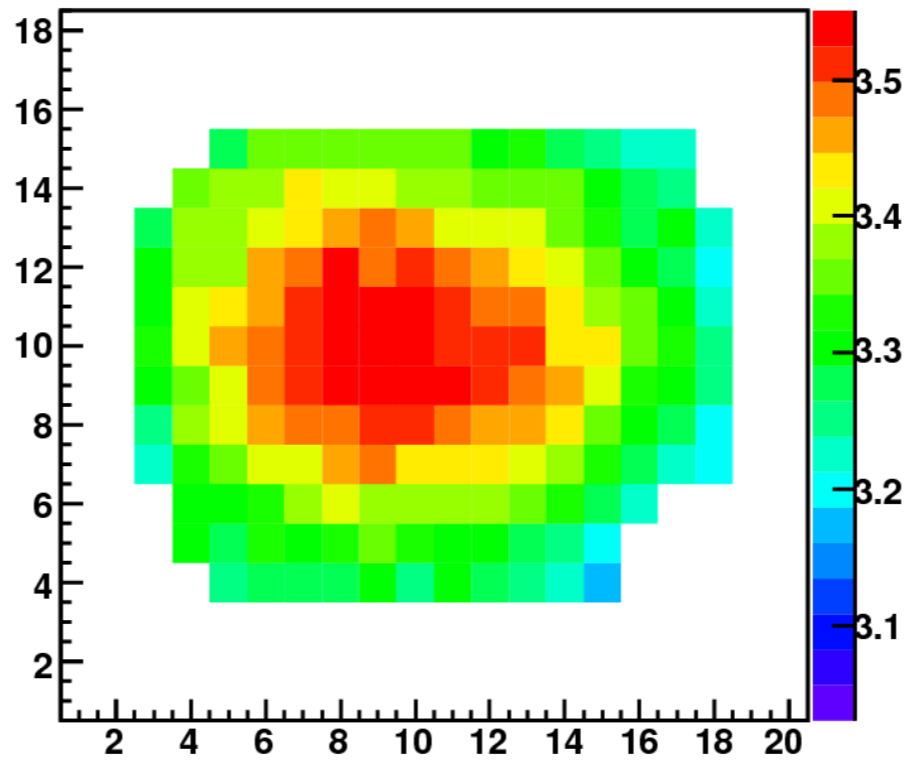
uniformity in a pixel



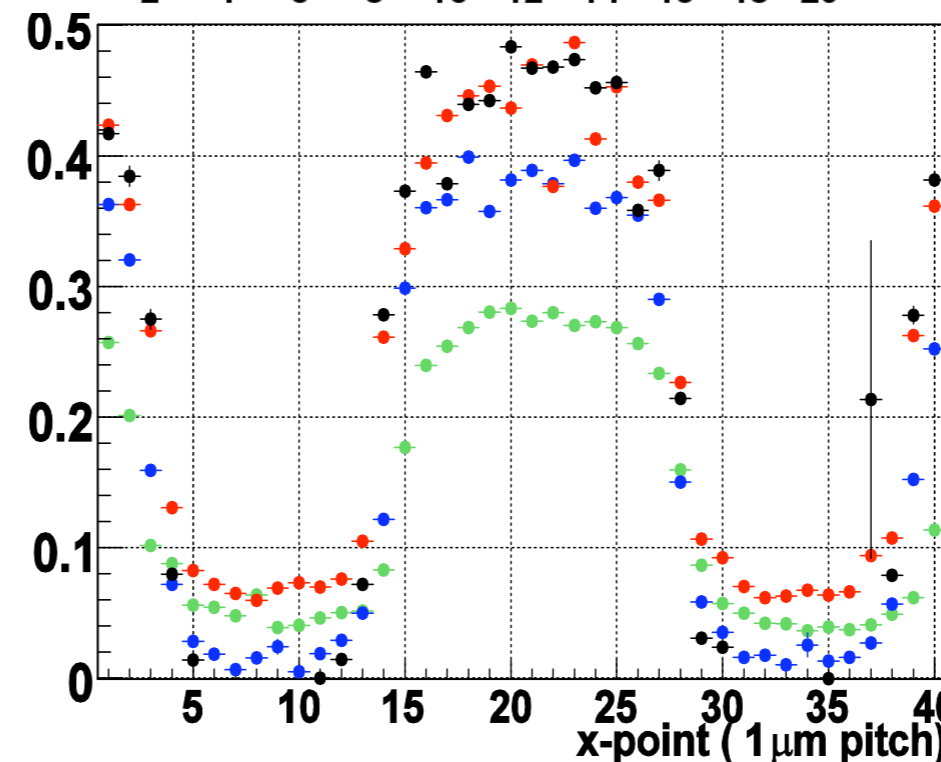
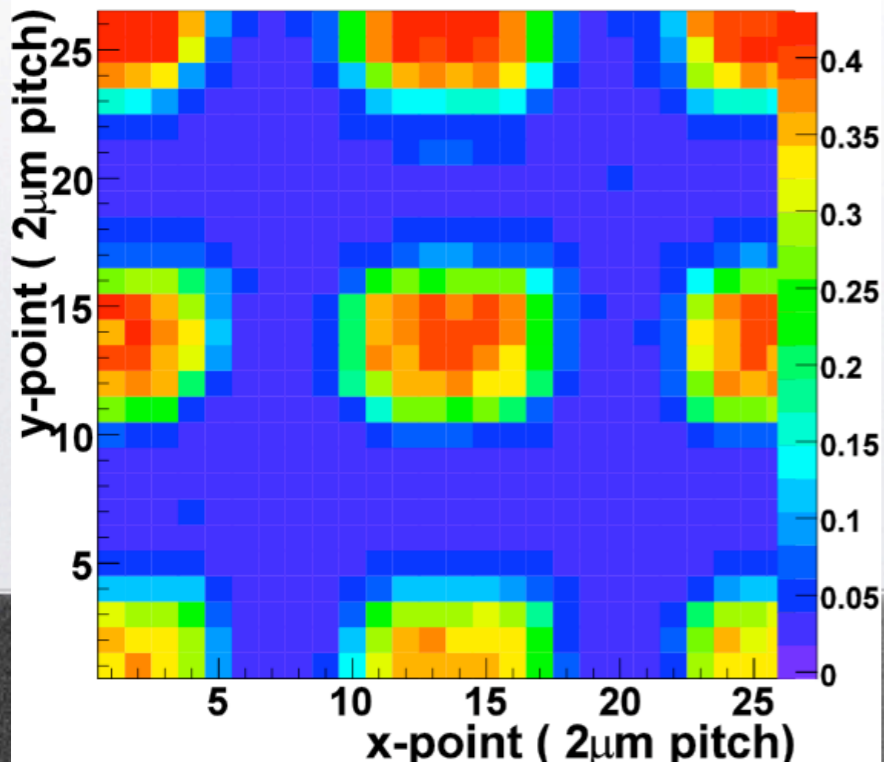
- tested by laser shot of $1\mu\text{m}$



Gain



uniform response in a pixel



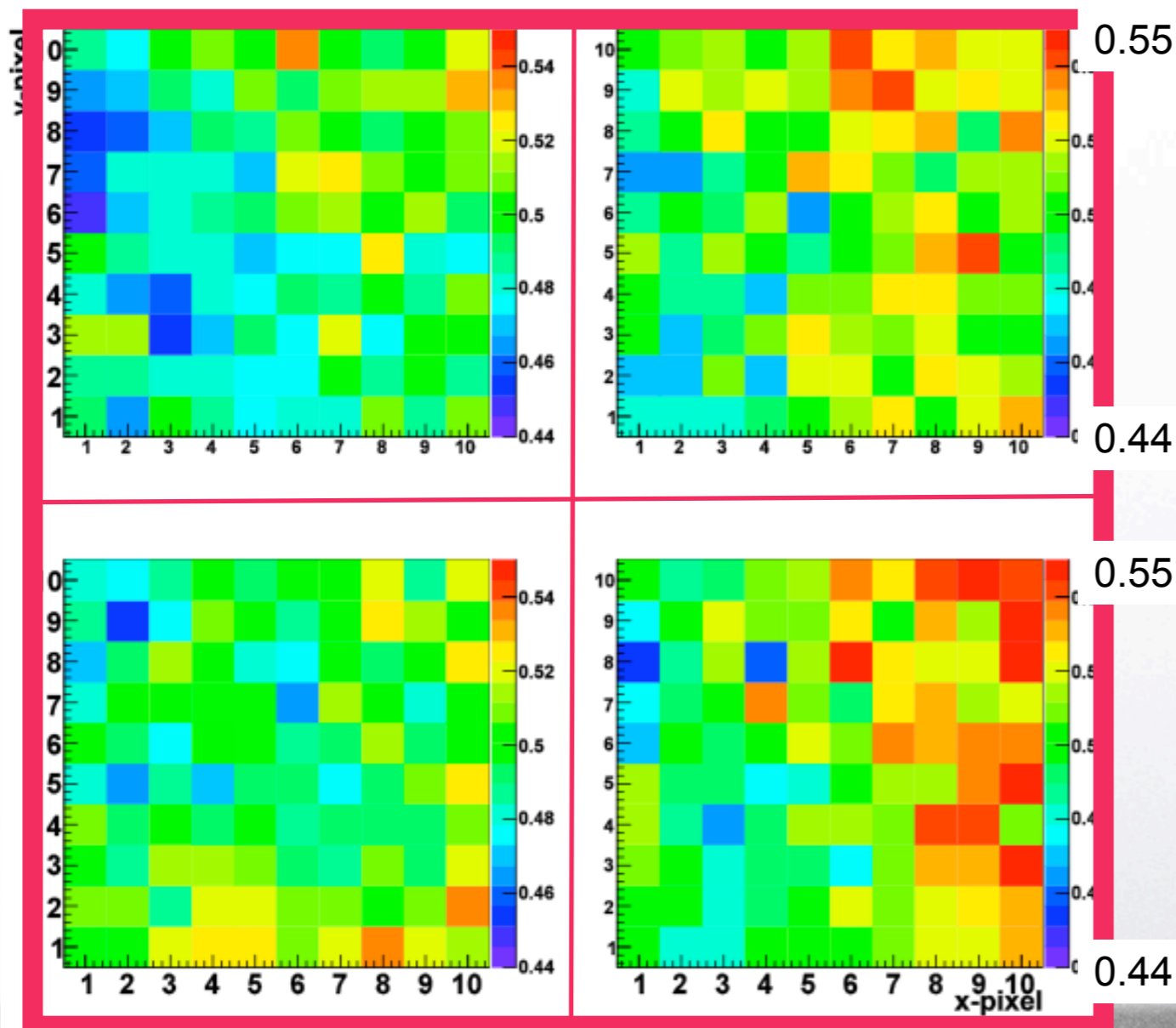
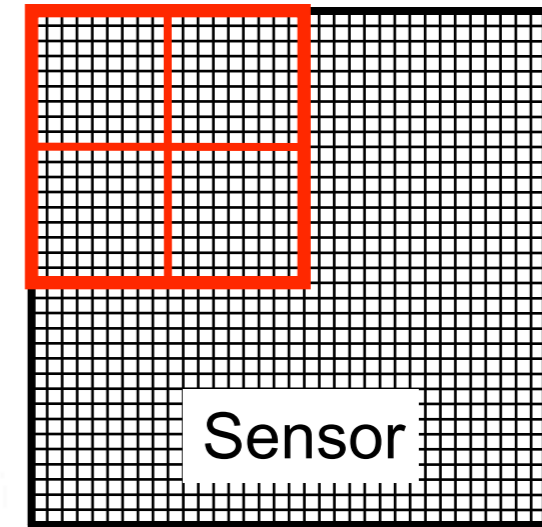
stable with V_{bias}



uniformity in pixels



- pixel uniformity is tested
- 20 x 20 pixels

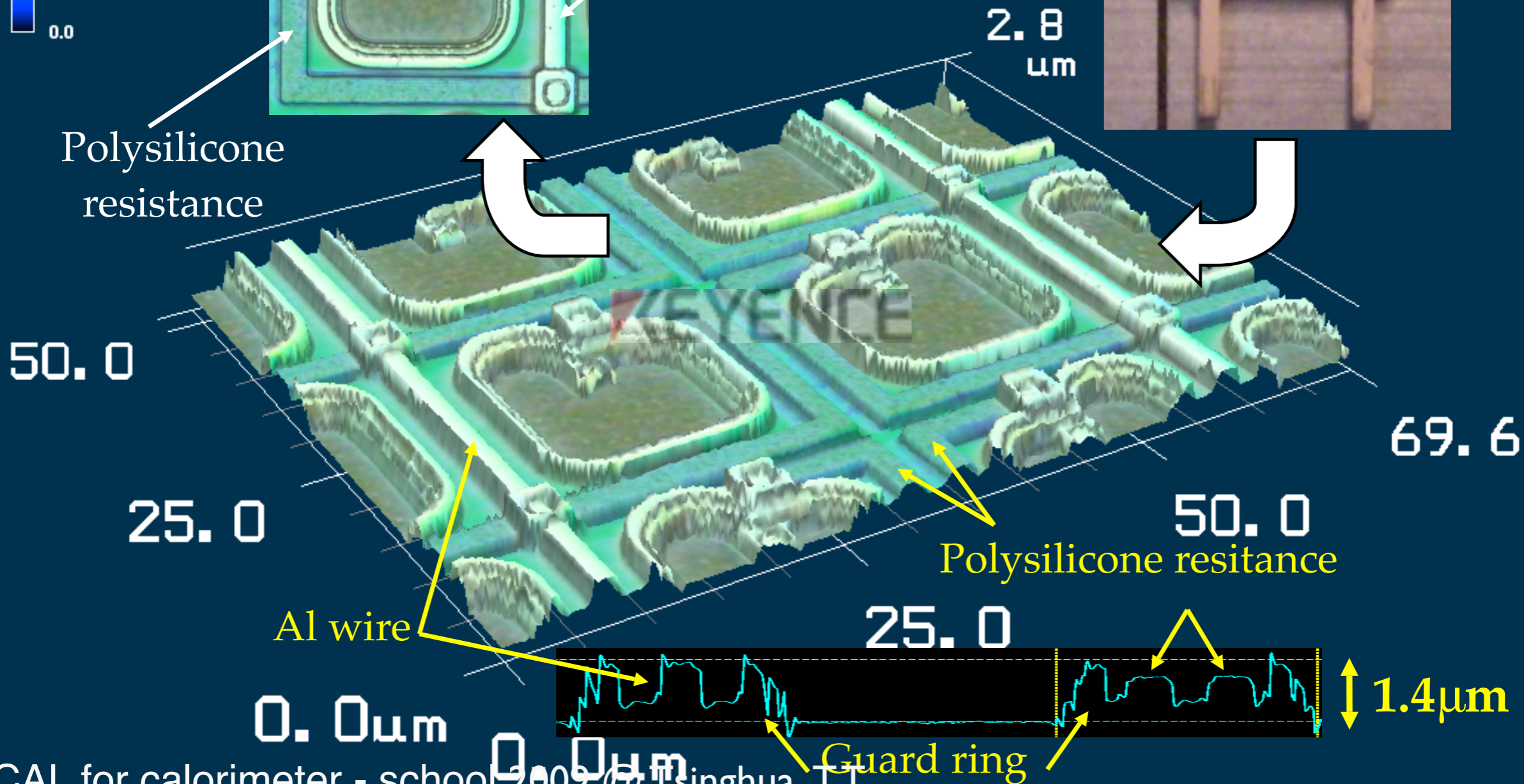
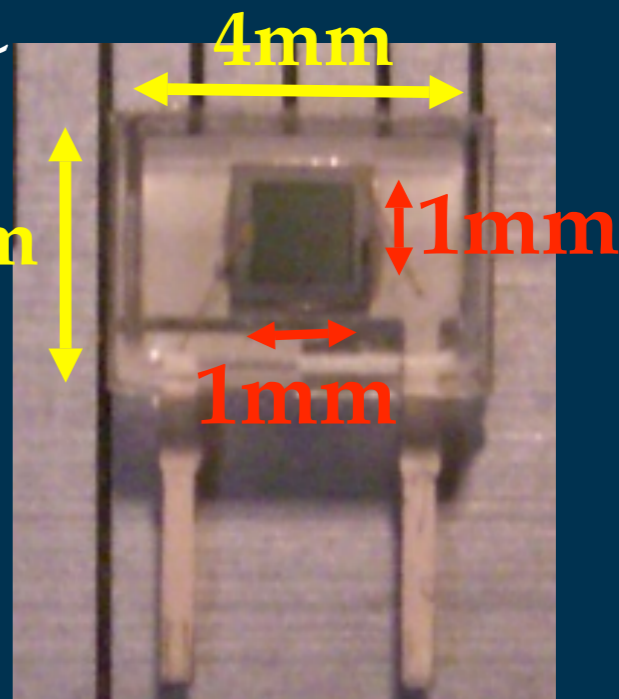
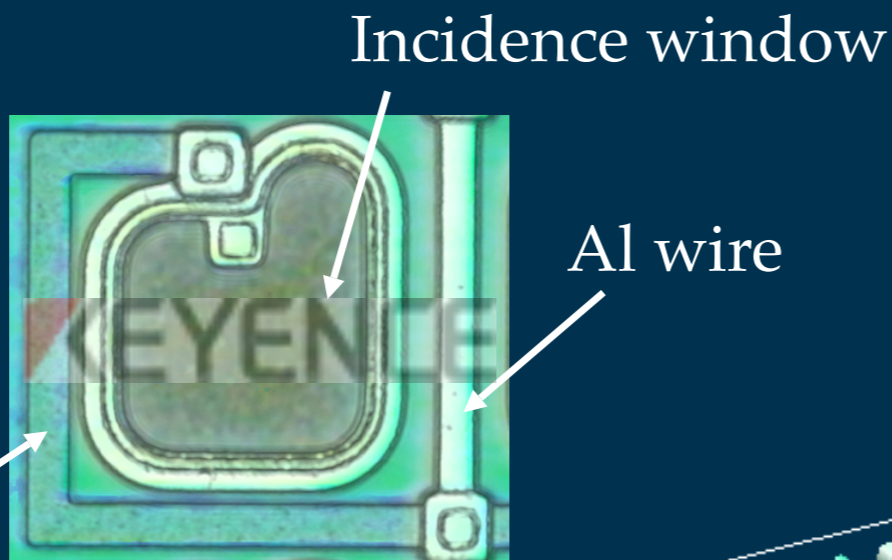
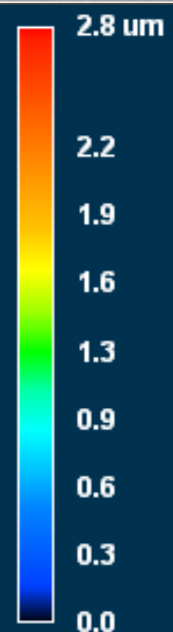


very small variation
3%



microscope picture

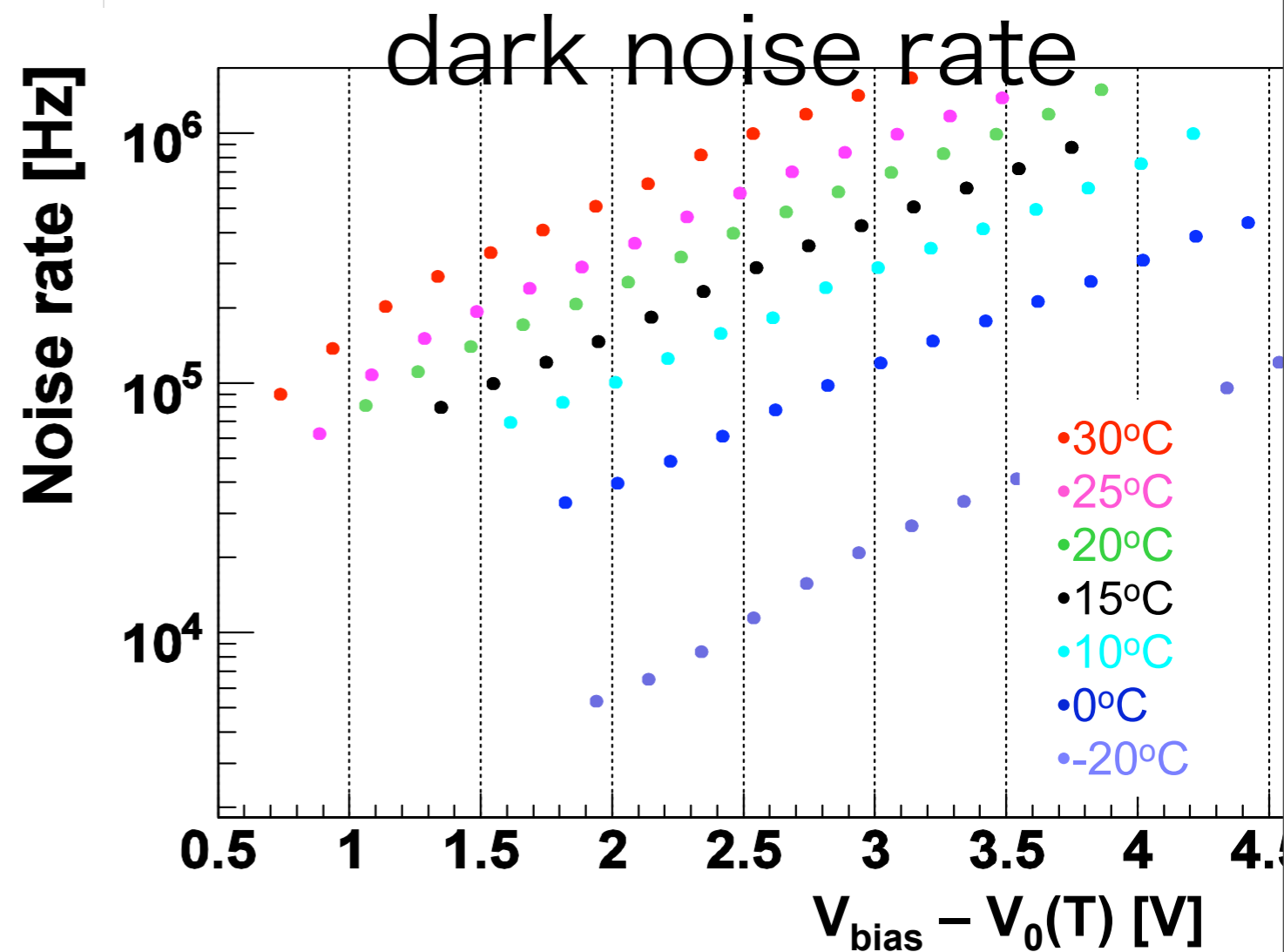
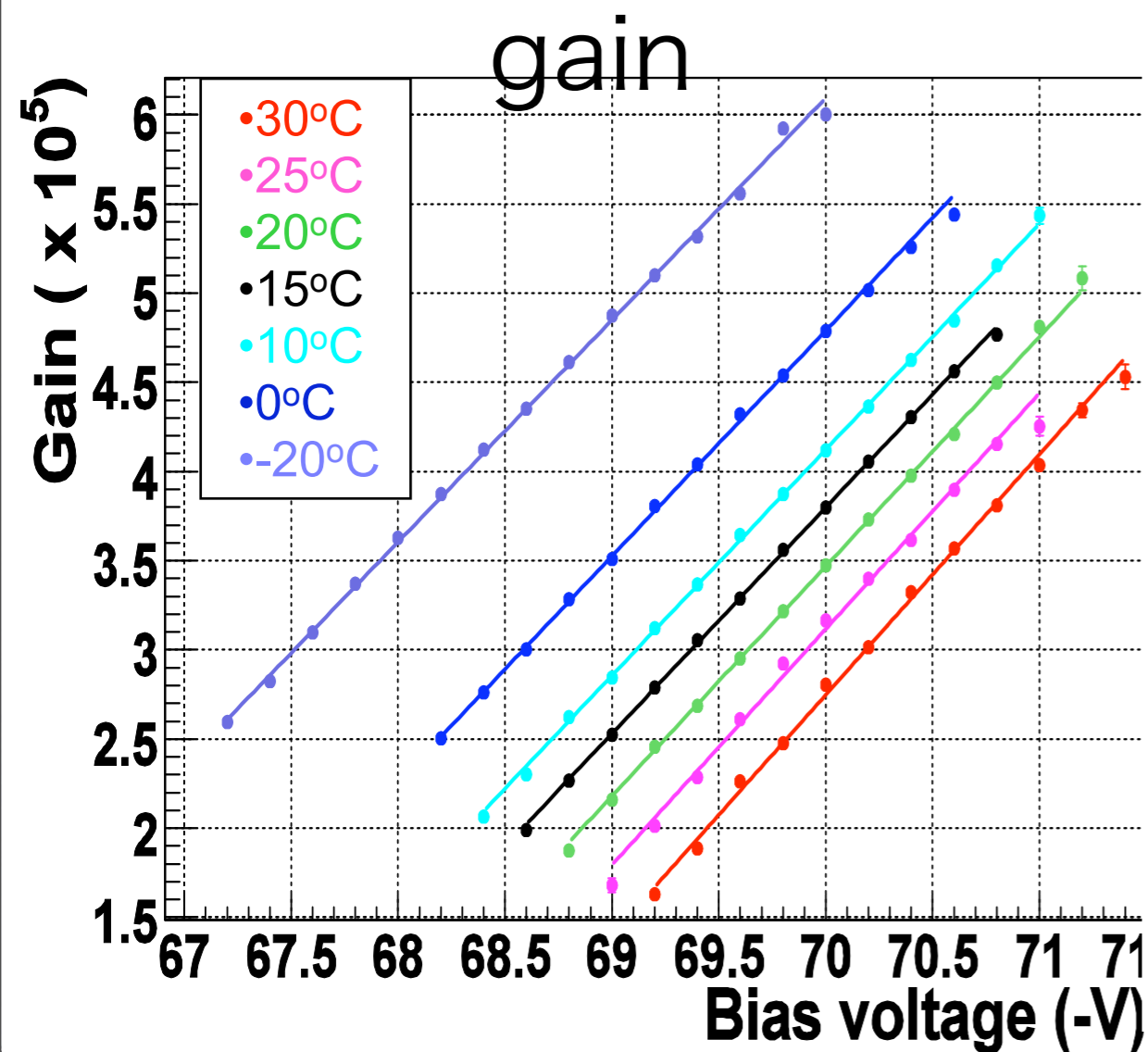
The surface structure of MPPC





temperature dep. ← | →

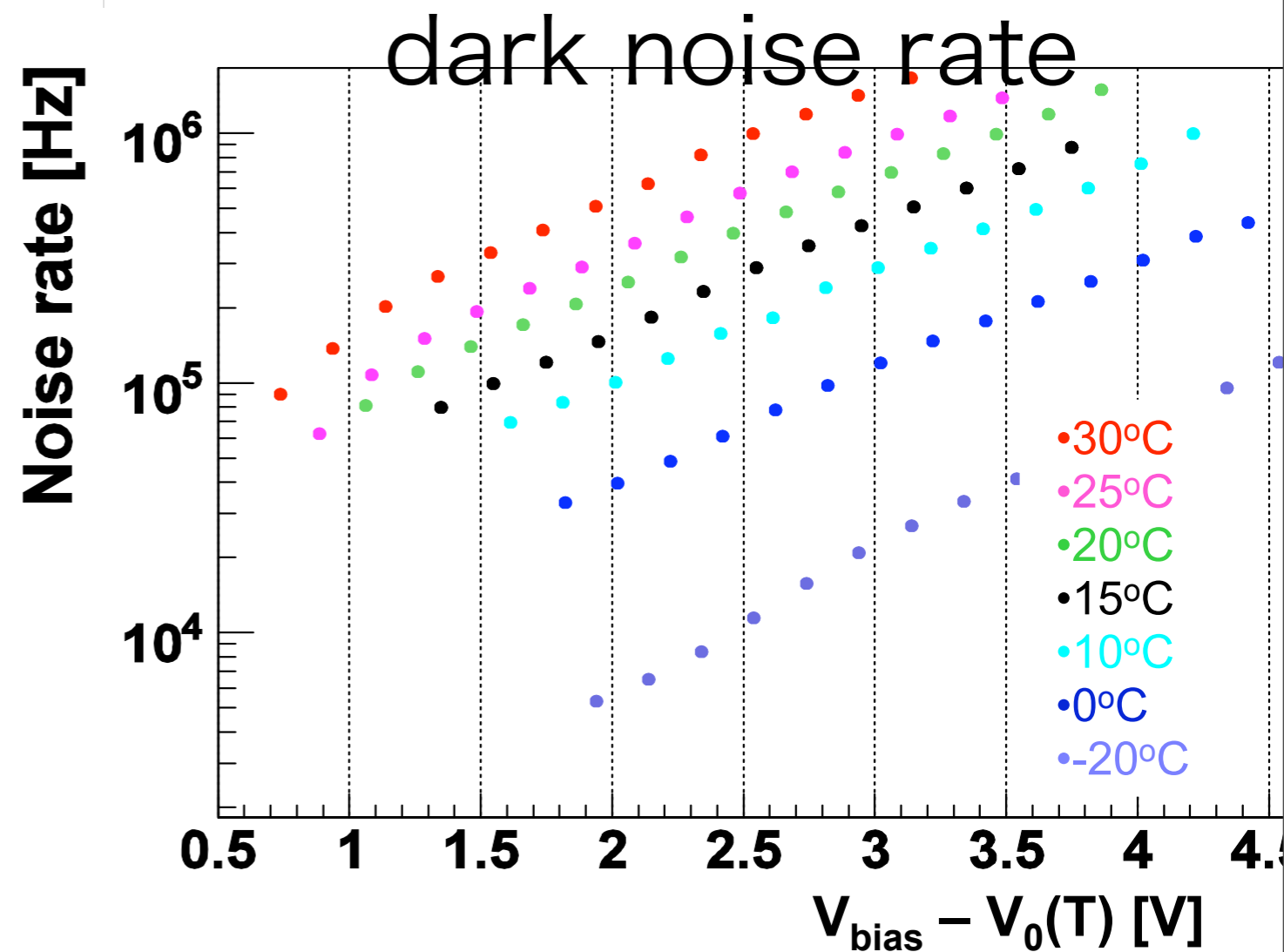
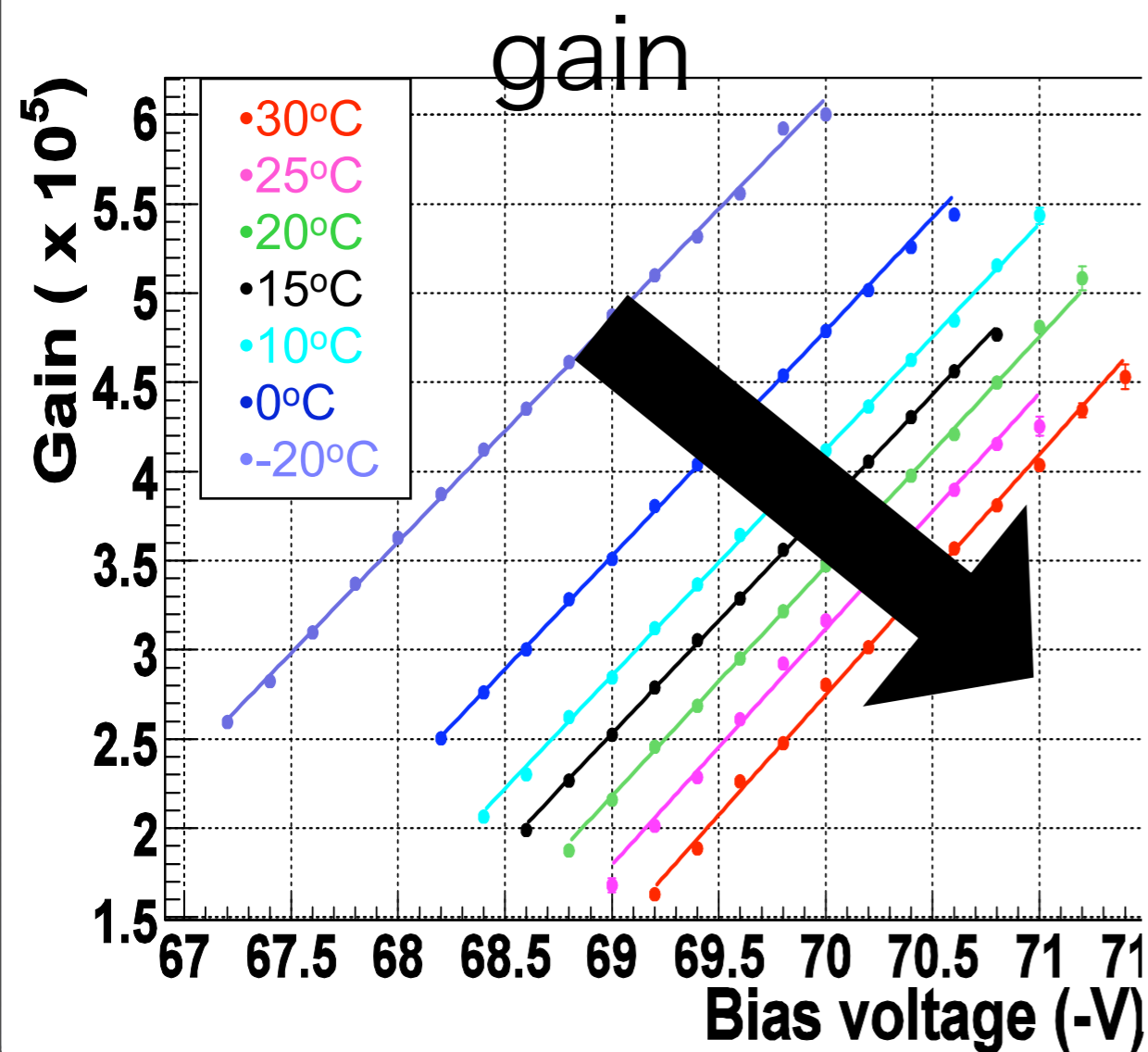
- Gain depends of Temp. with $\sim -2\%/K$.
- DARK noise rate dep. Temp. with $+$ coef.





temperature dep. ← | →

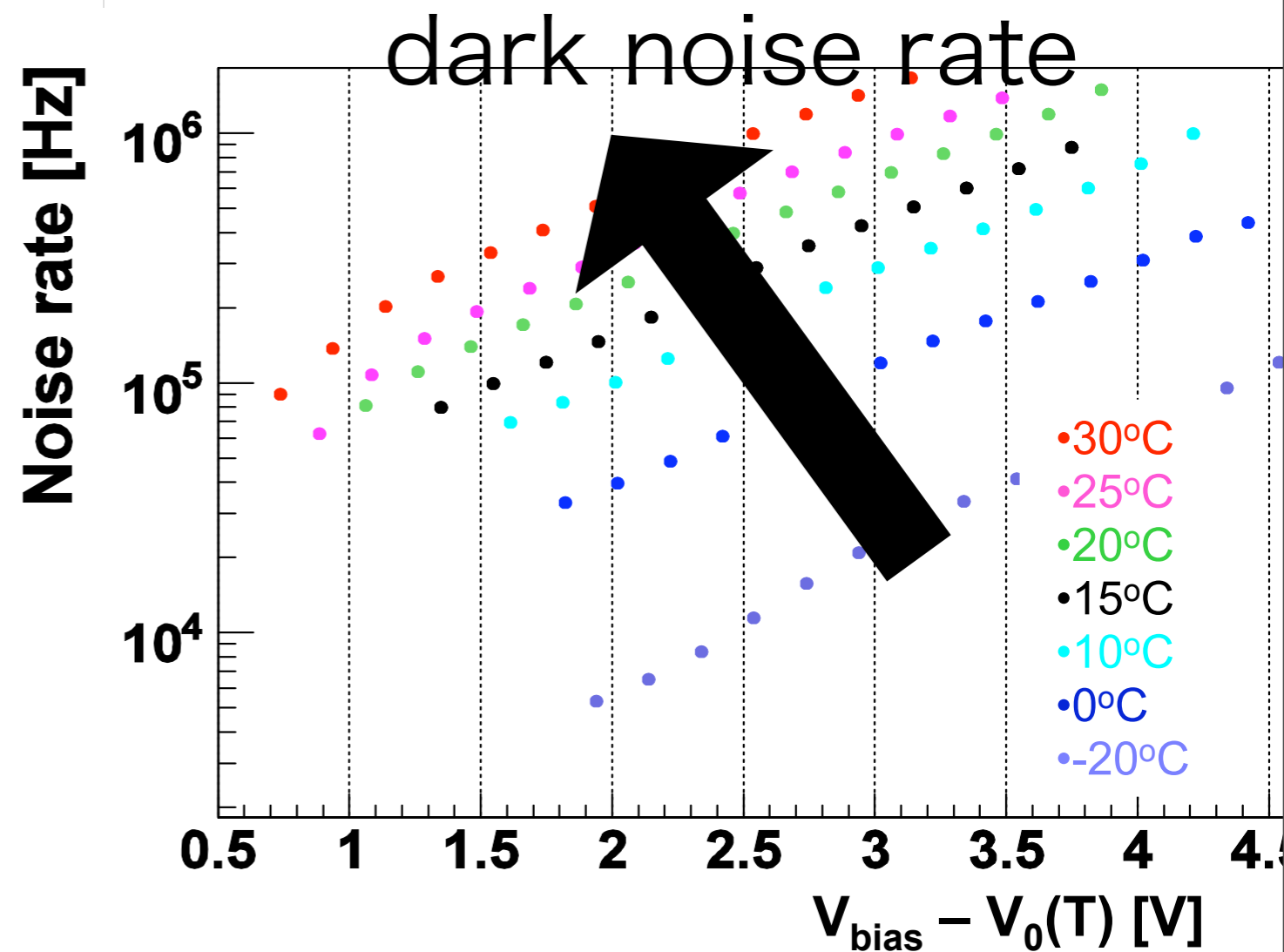
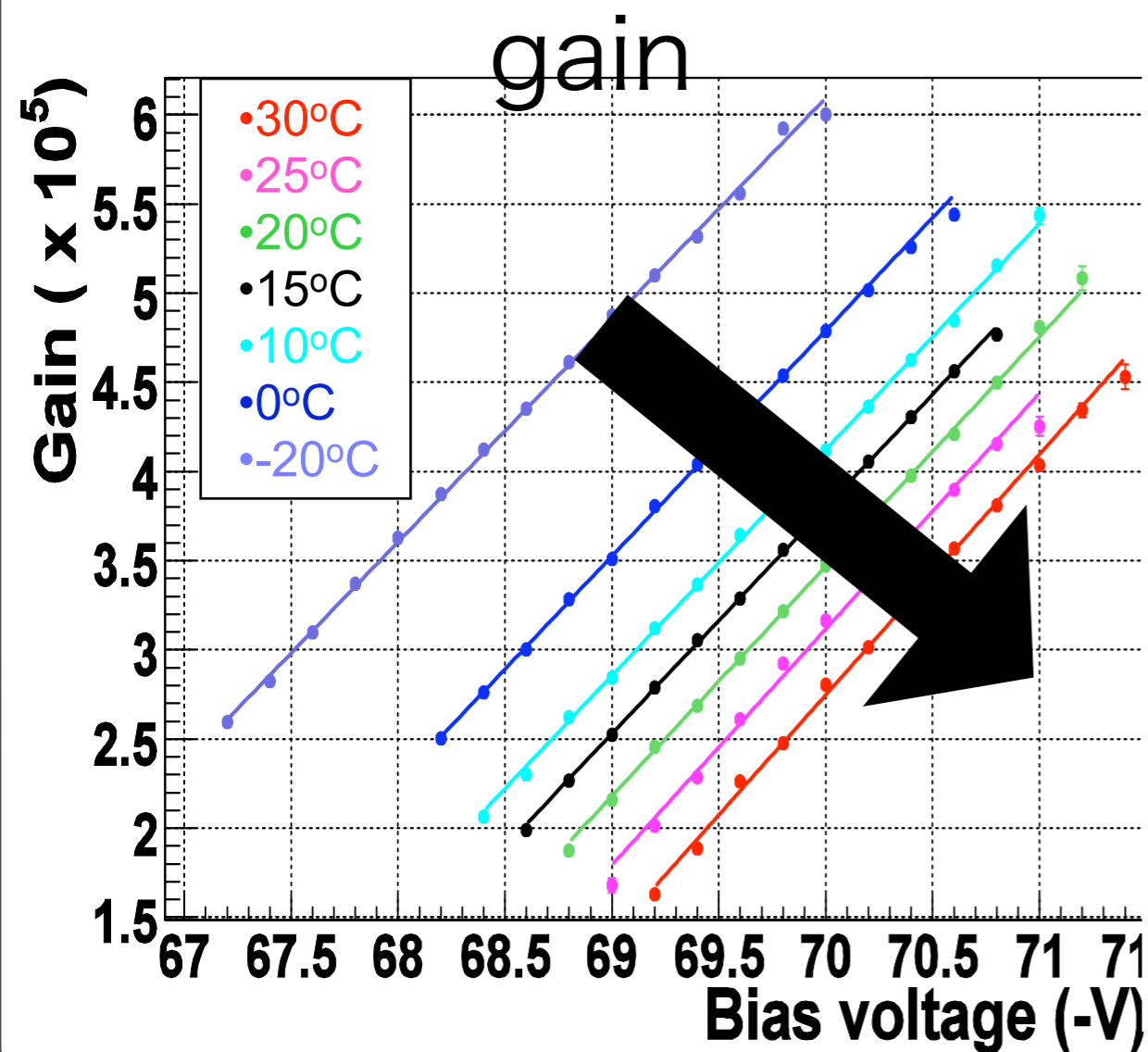
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temperature dep.

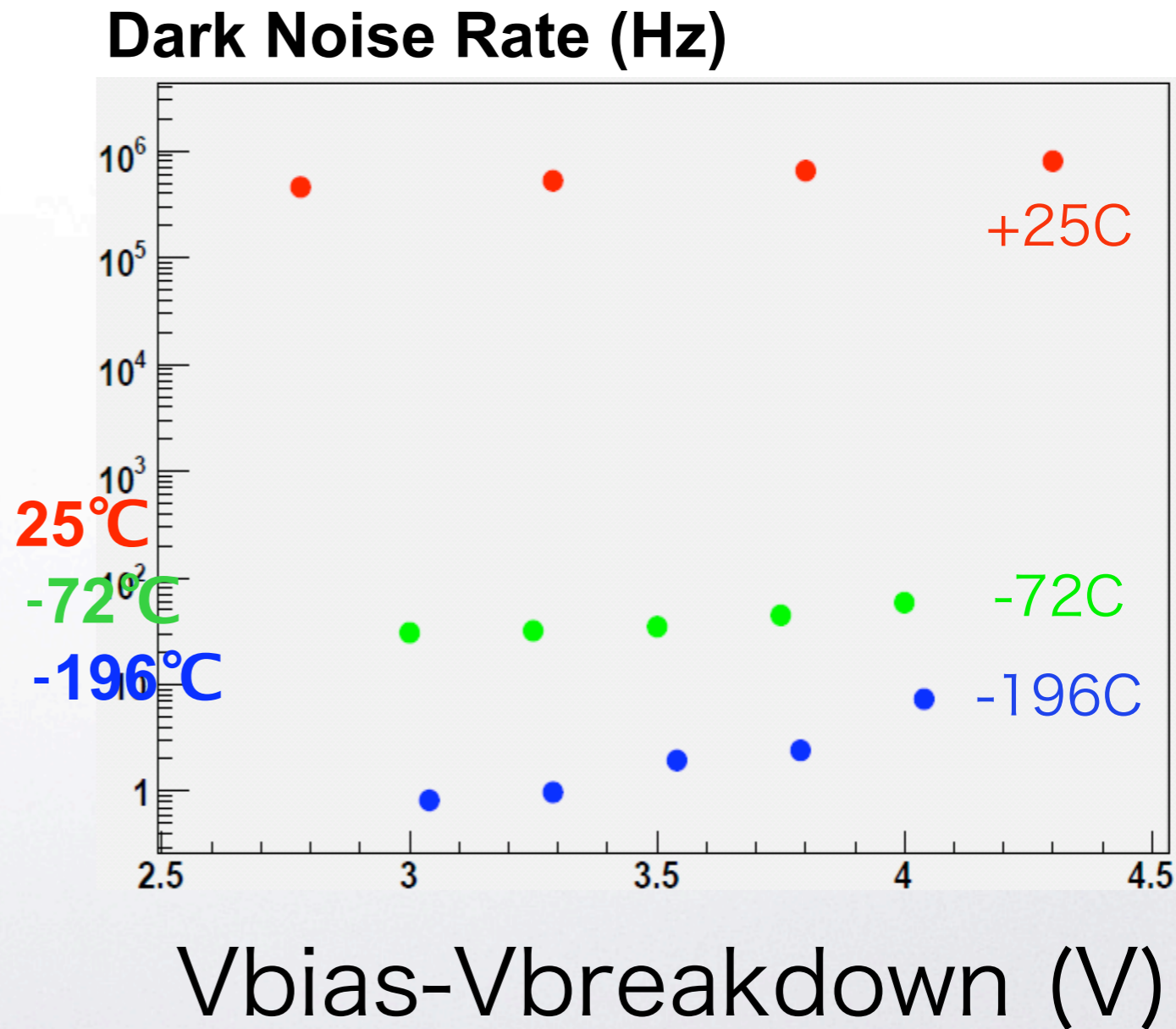
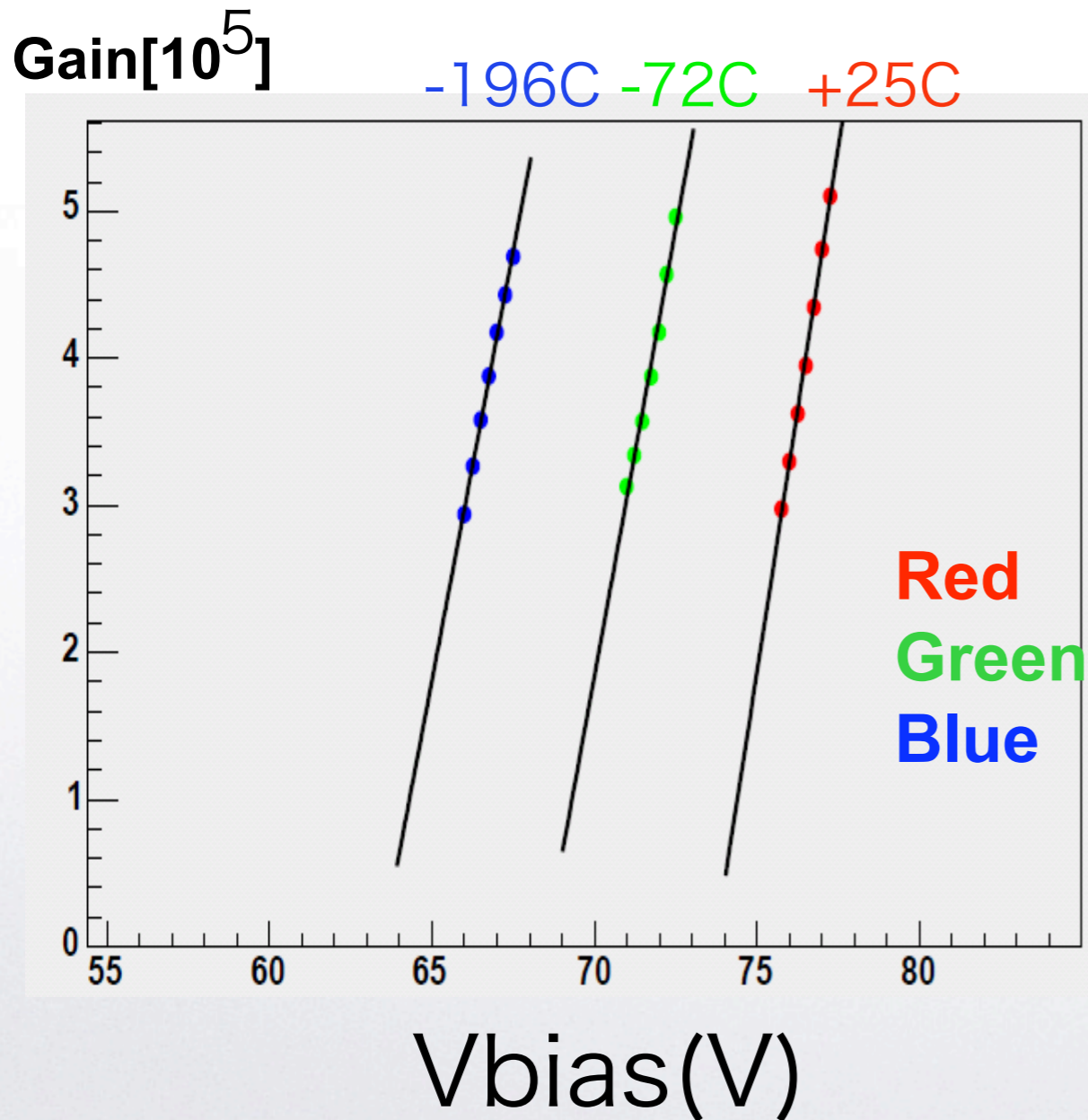
- Gain depends of Temp. with $\sim -2\%/K$.
- DARK noise rate dep. Temp. with $+$ coef.





temperature dep. 2

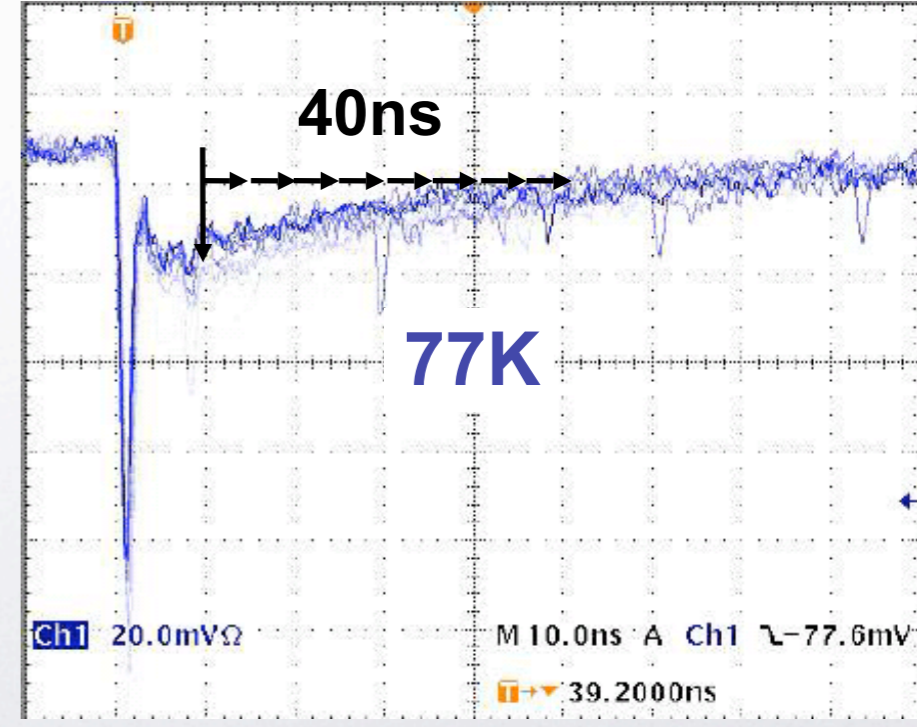
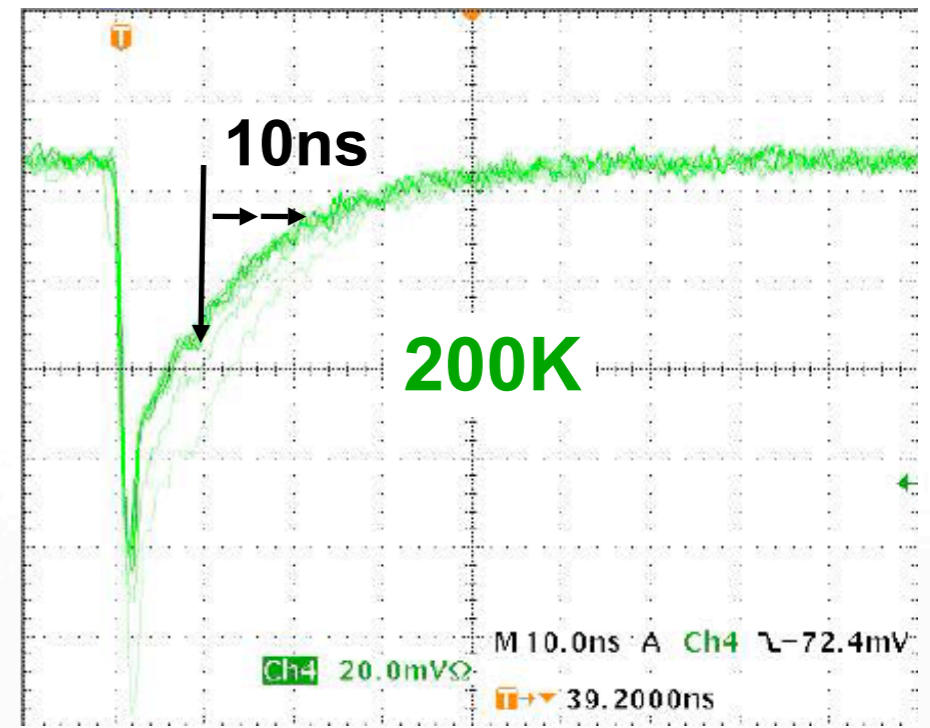
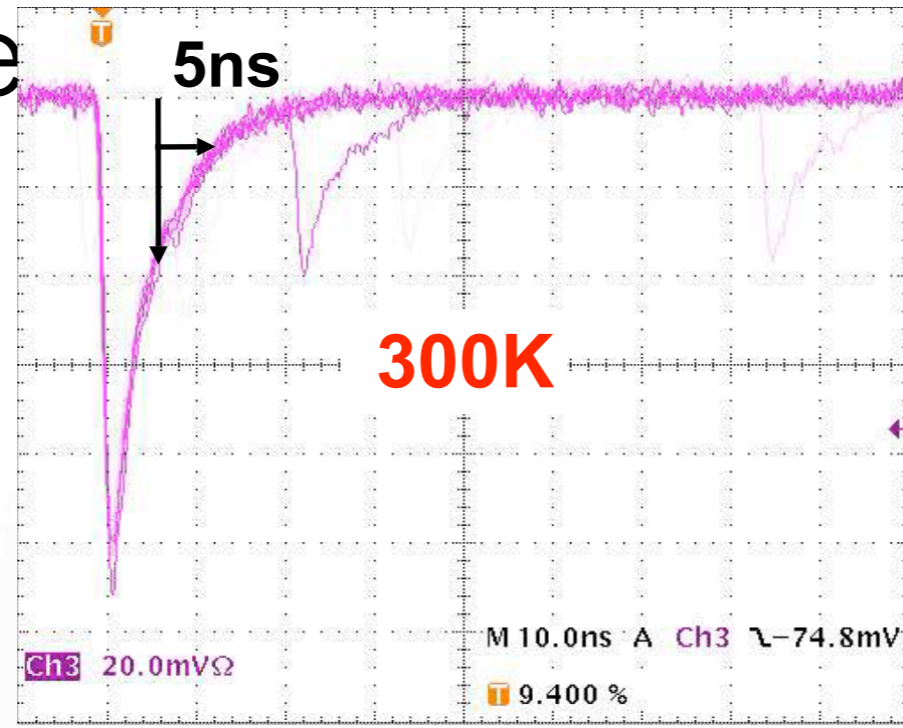
- lower temperature
- capacitance stays const.





temperature dep. 3

- signal shape
- time const. of tail is understood
- by $Rq(T)$

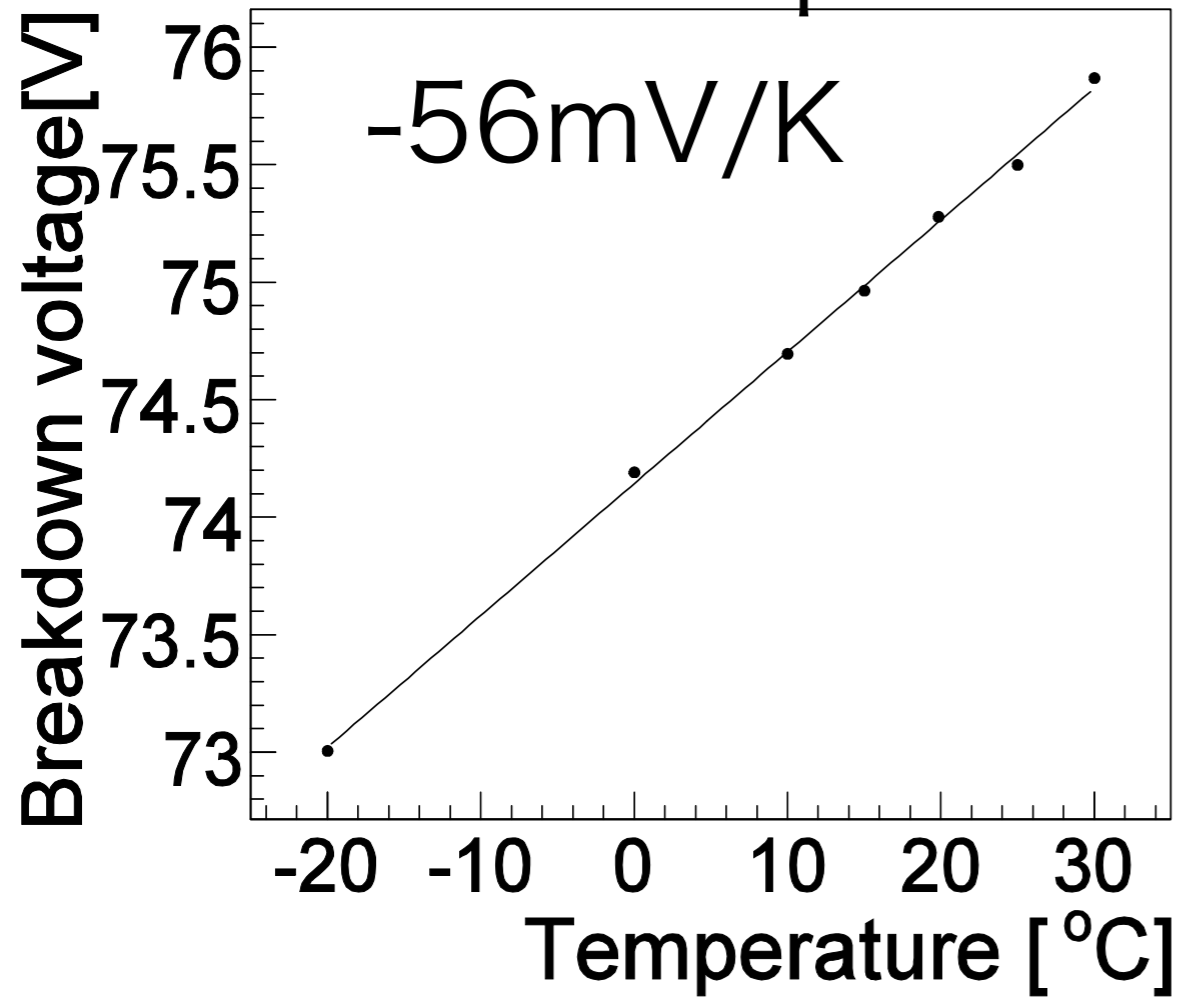


	Resistance (R)	Capacitance (C)	R x C
300K	0.21MΩ	22.1fF	4.6ns
200K	0.40MΩ	22.0fF	8.8ns
77K	1.68MΩ	21.3fF	35.8ns

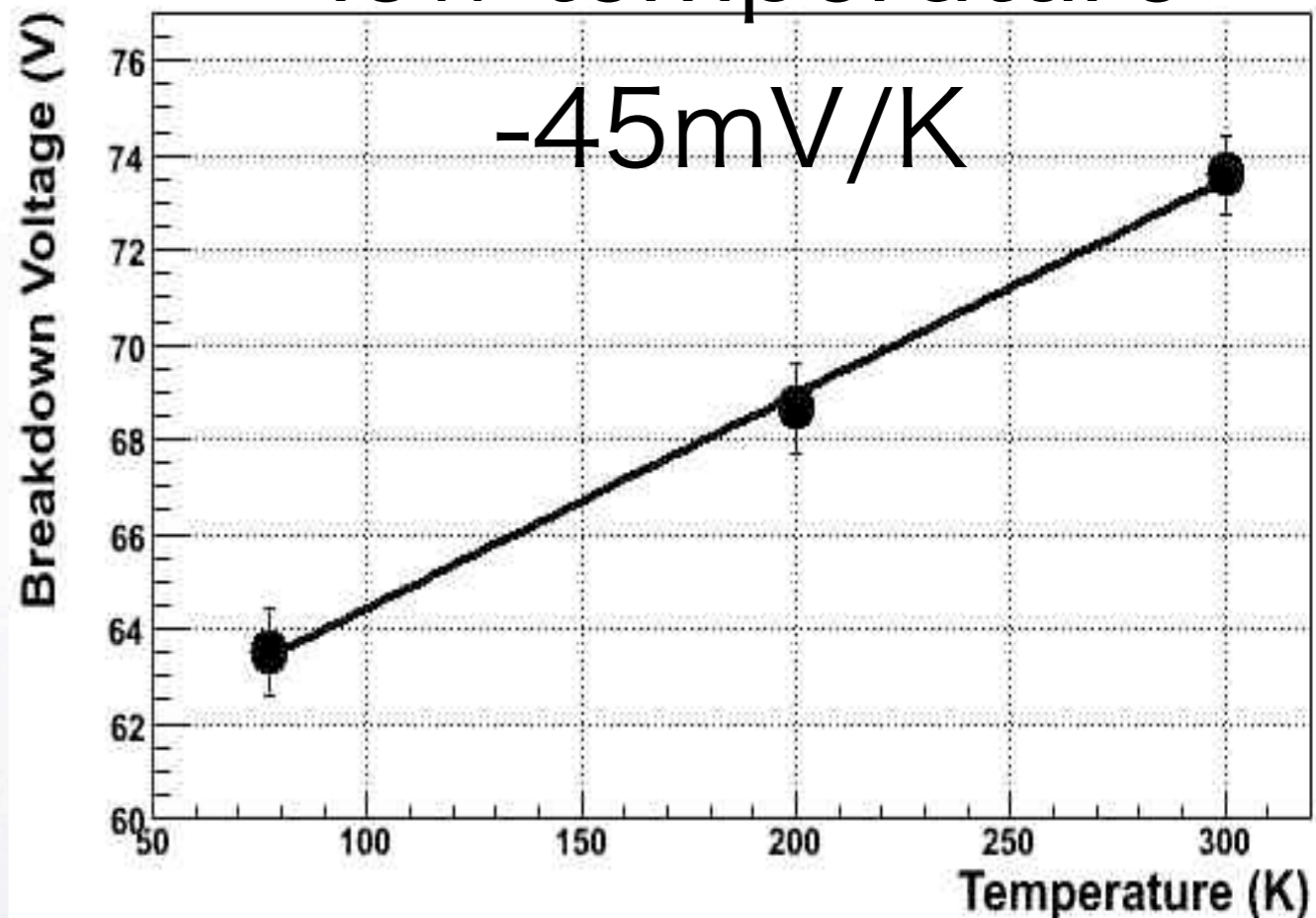


- Breakdown Voltage vs Temperature

room temperature



low temperature



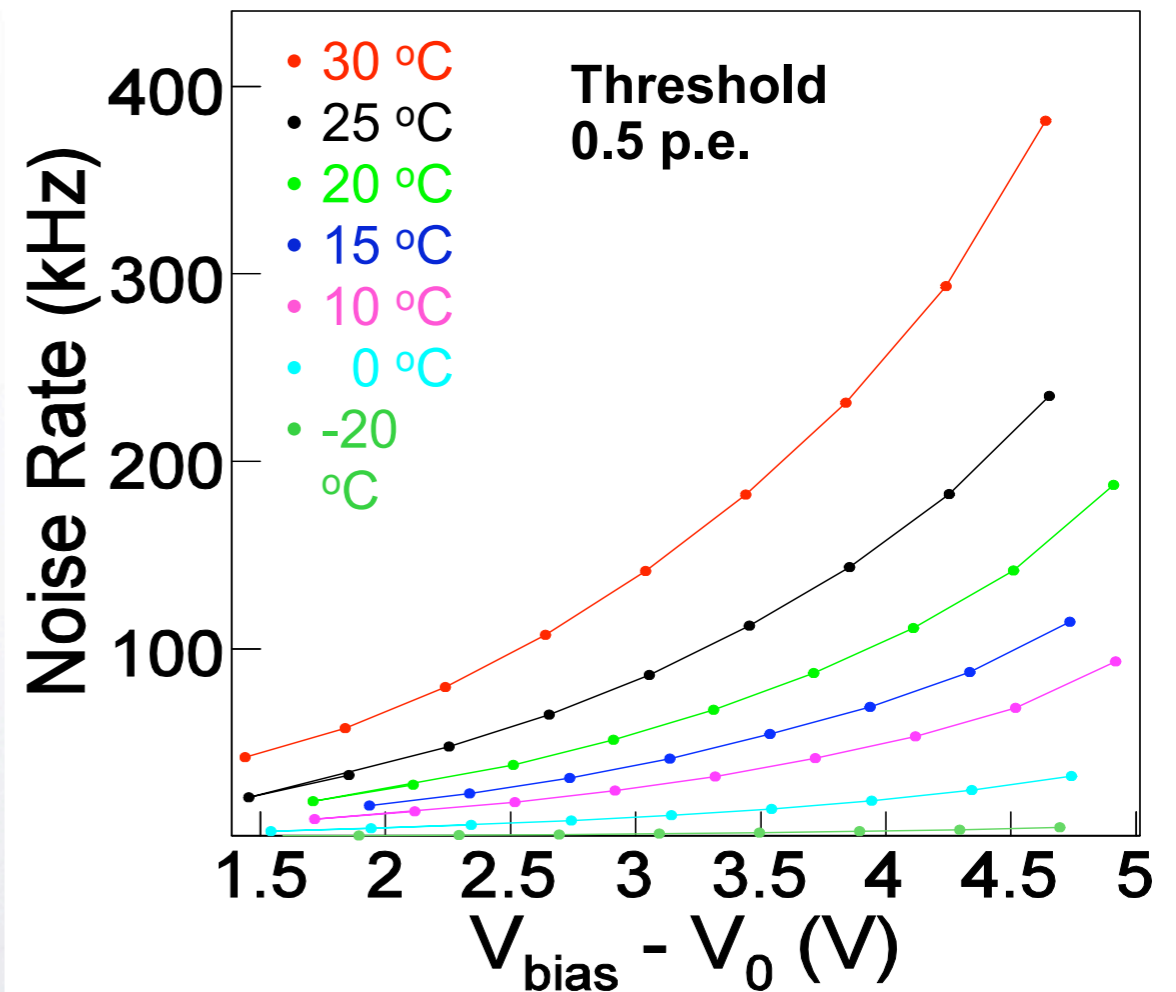
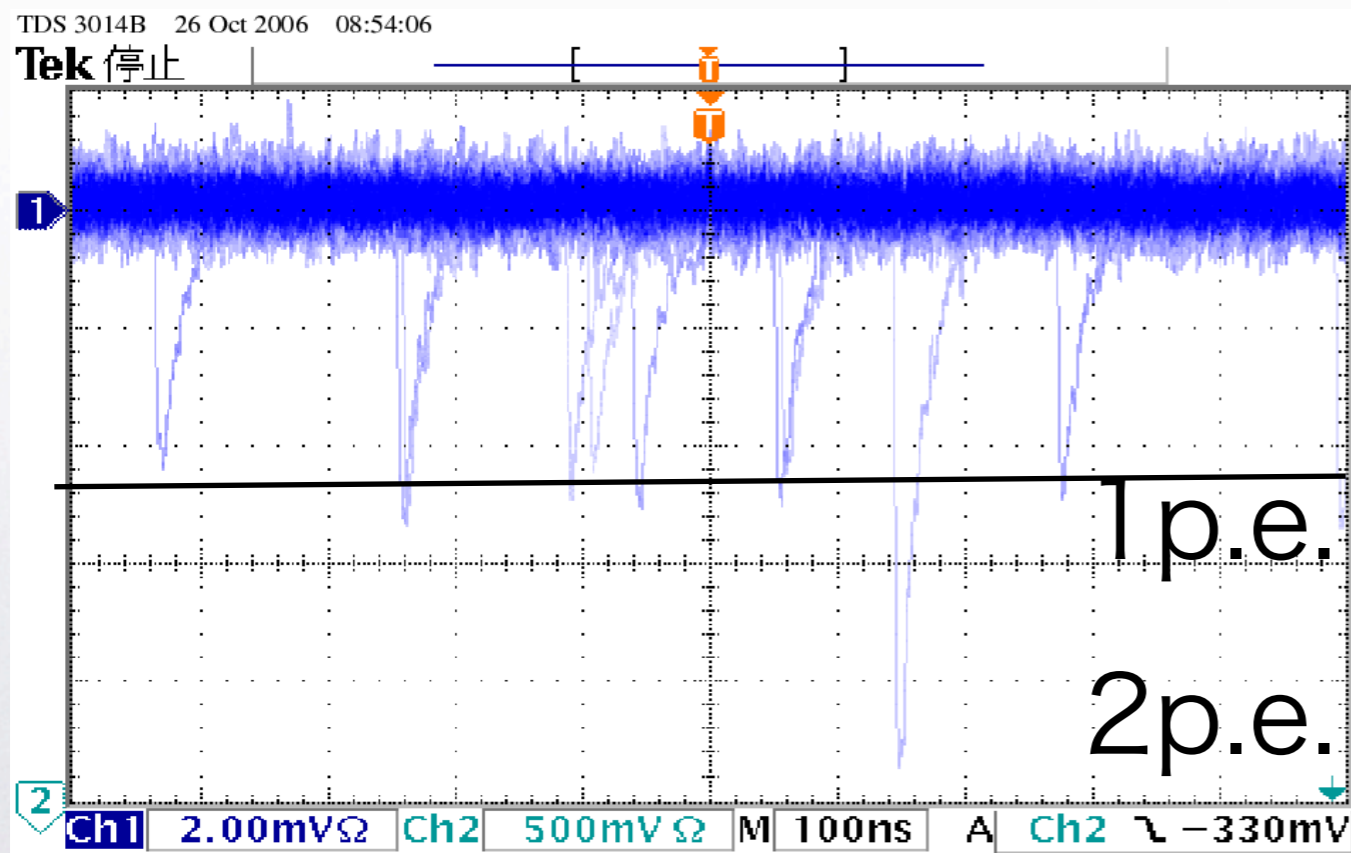
-196C

-72C

+25C

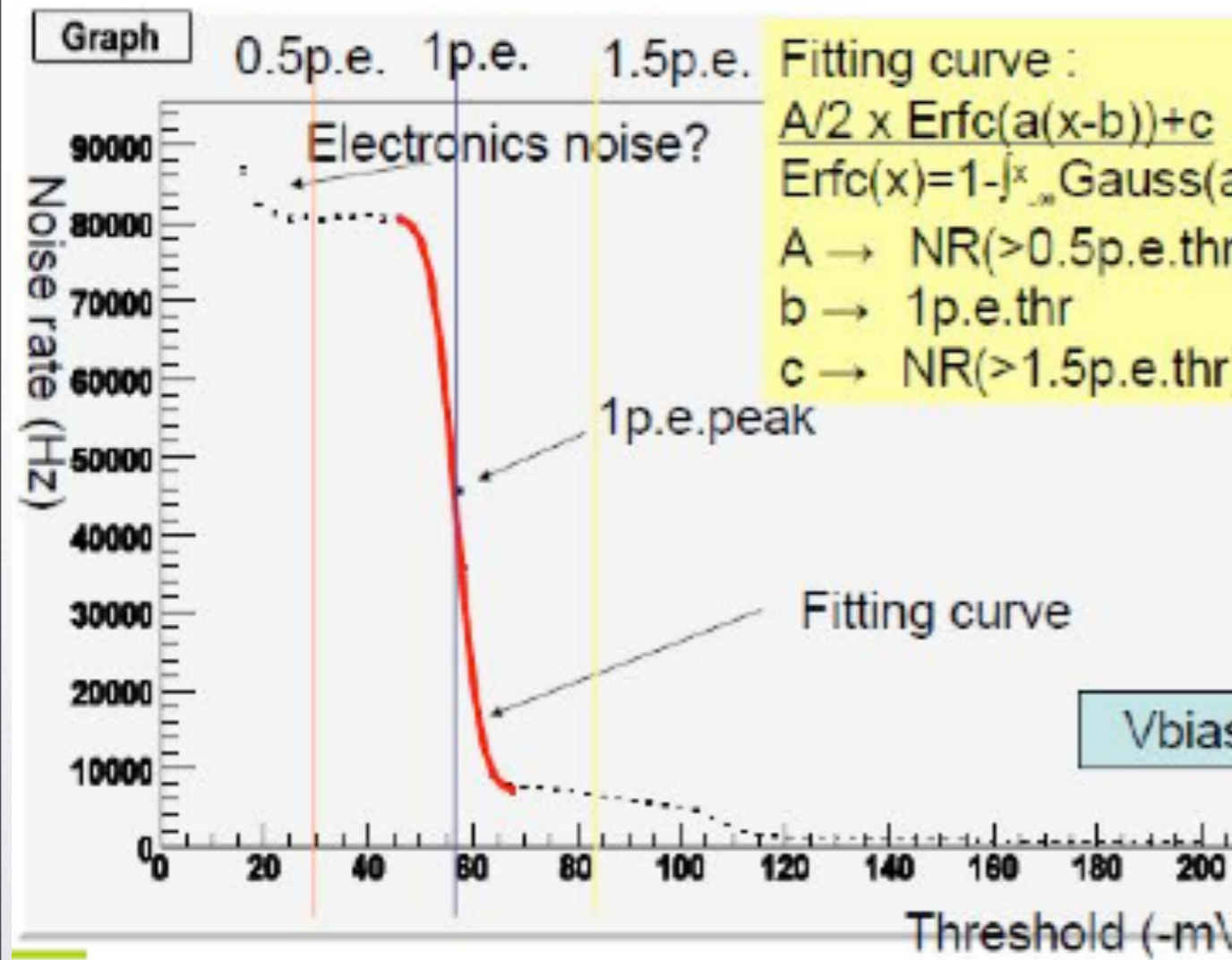
Dark noise

- silicon device
- thermal electron may occur avalanche in a pixel
- make an 1 p.e. equivalent signal
- ~ 1 MHz

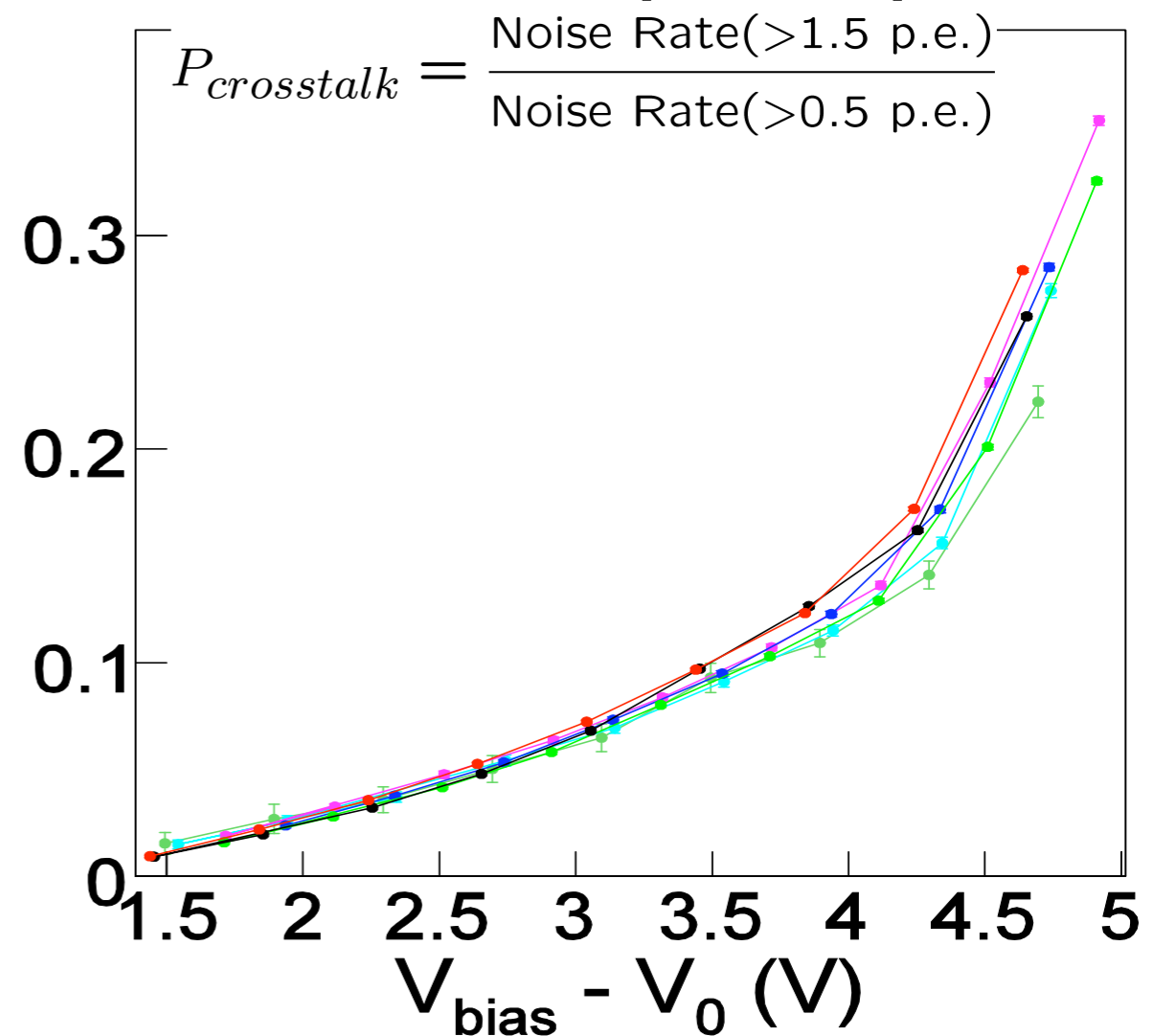


Dark noise 2

- threshold curve
- 2 p.e. signals due to cross talk
no temp. dep.

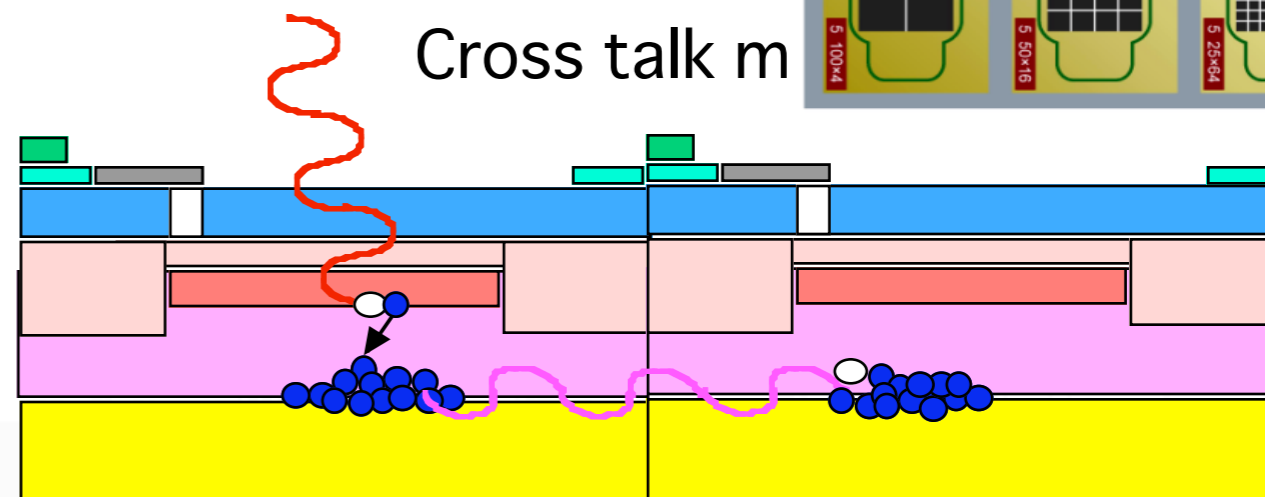
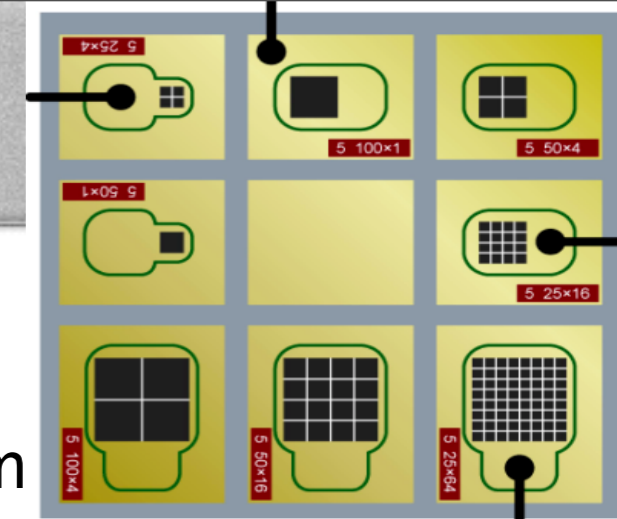


Cross-talk probability

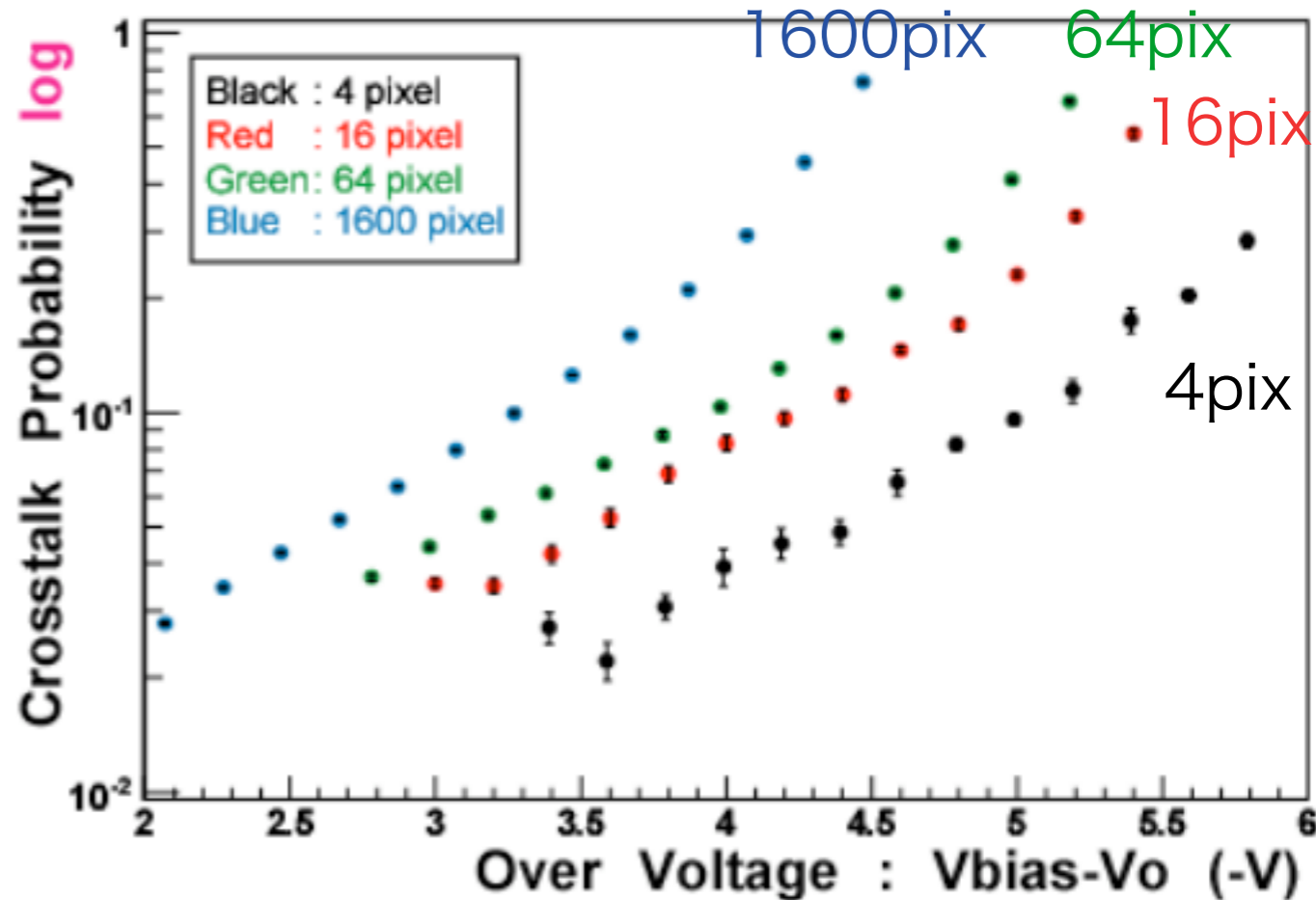
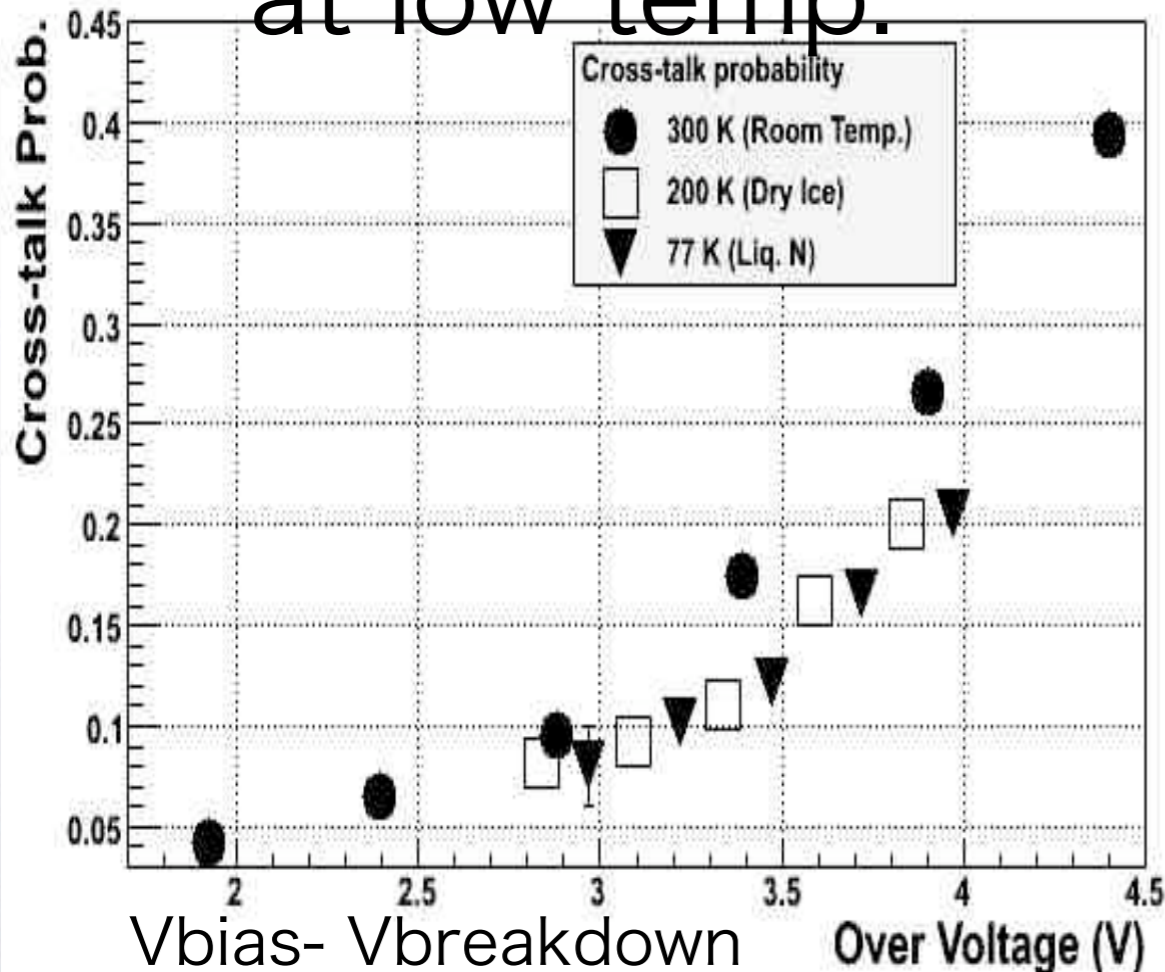


Cross talk

- between (neighboring) pixels
- 4, 16, 64, 1600 pix



at low temp.

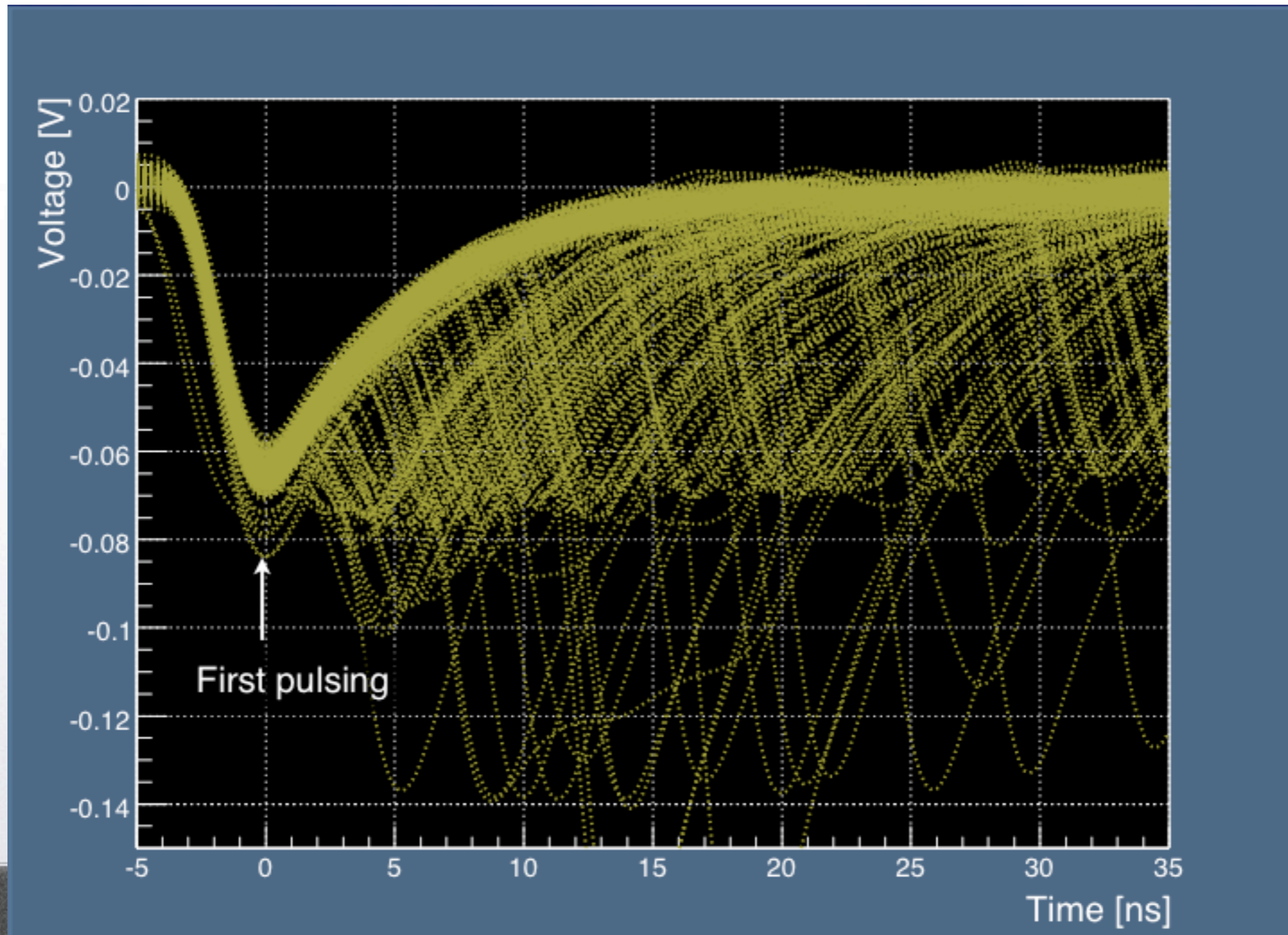




signals by Oscillo.



- three lines: cross talk pulses
- after pulses and accidentals

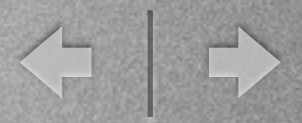


after
pulse

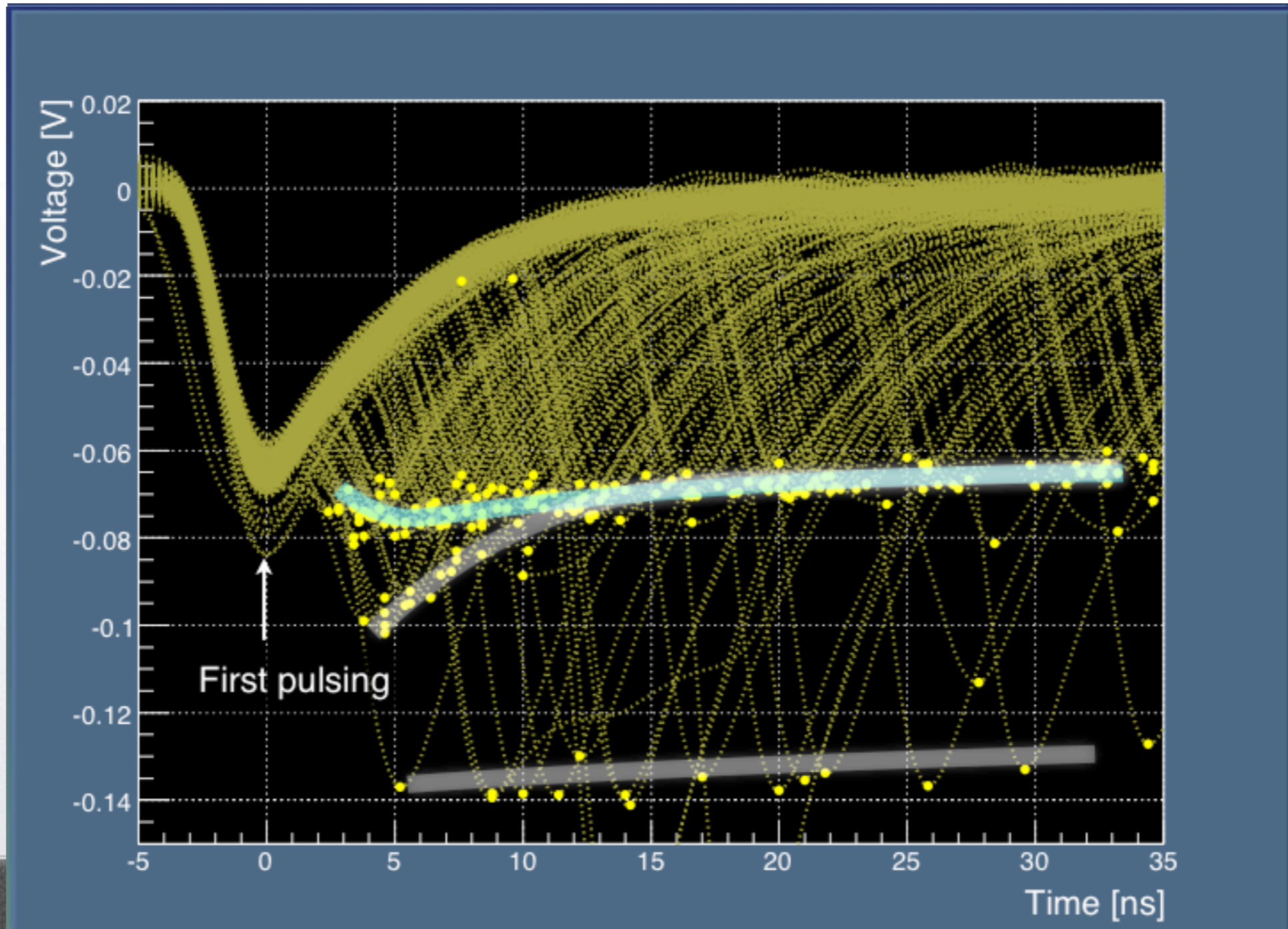
cross
talk



signals by Oscillo.



- three lines: cross talk pulses
- after pulses and accidentals



after pulse

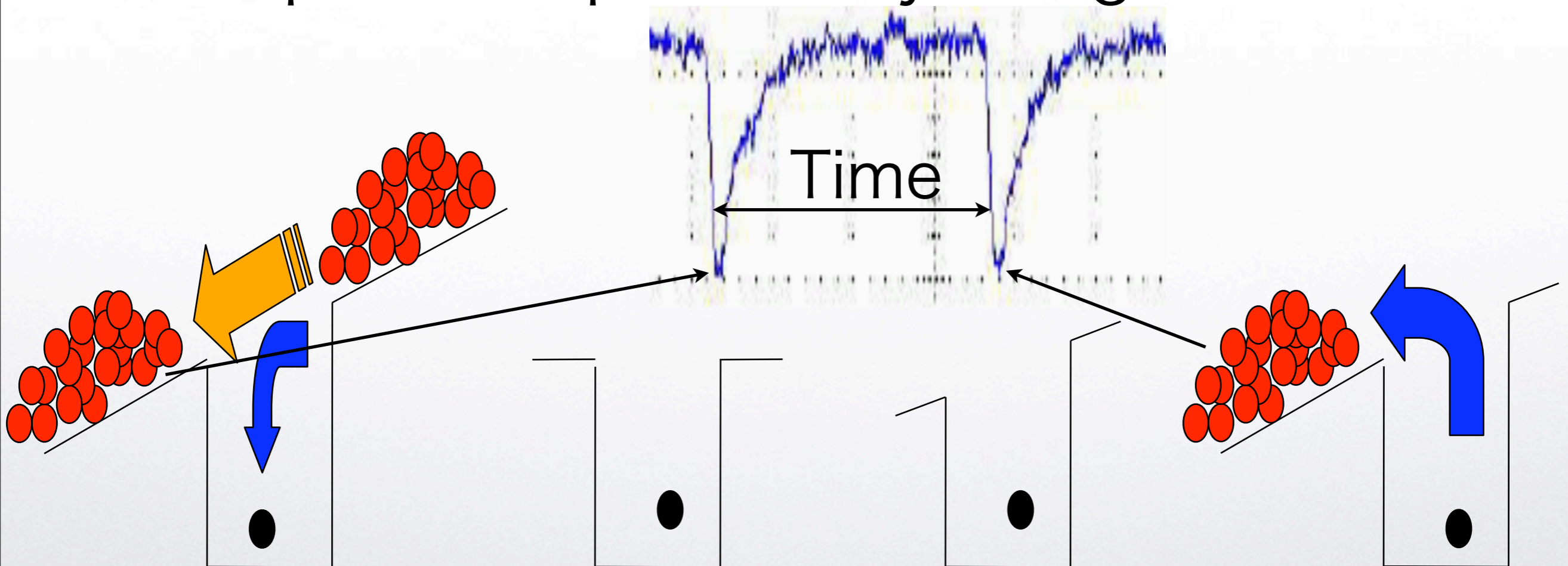
cross talk



After pulses



- Dark noise contains
- cross talk : 2 p.e. : light induced avalanche
- after pulse : 1 p.e. : delayed signals



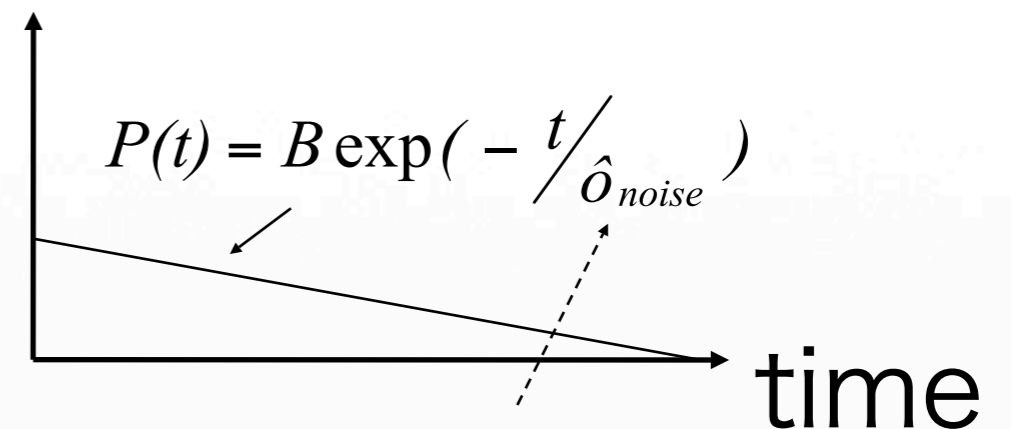
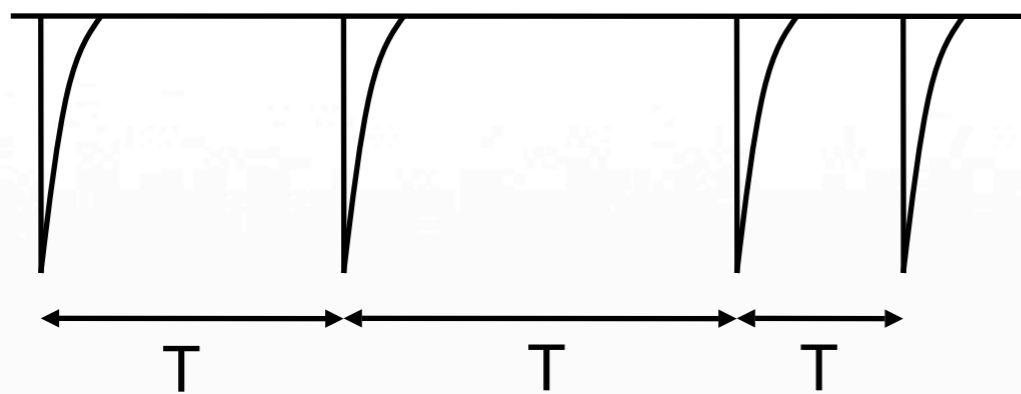


After pulses 2

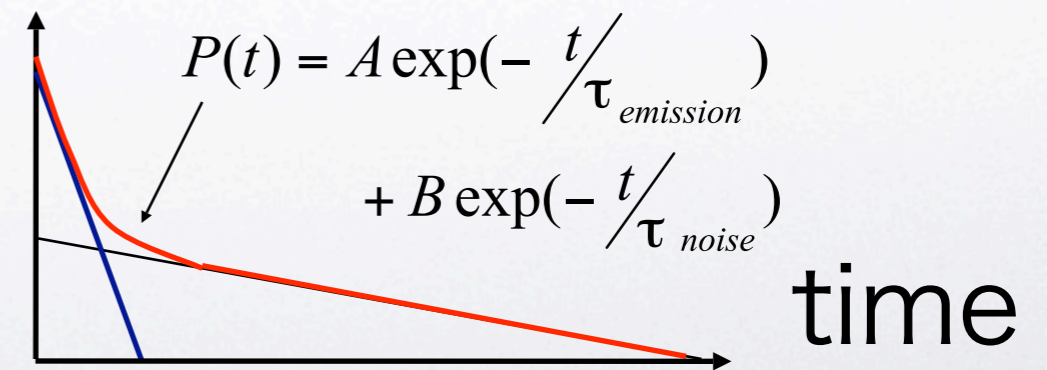
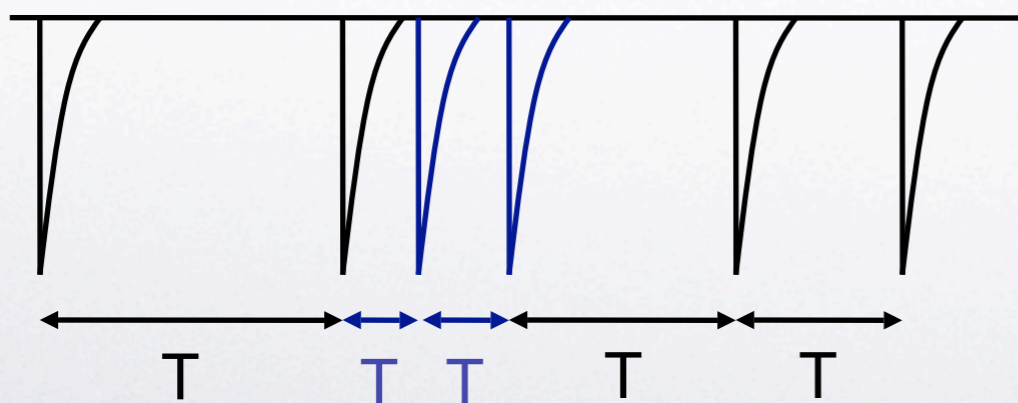


- difficult to separate from dark noise pulse

ideal case without after pulsing



real world with after pulsing



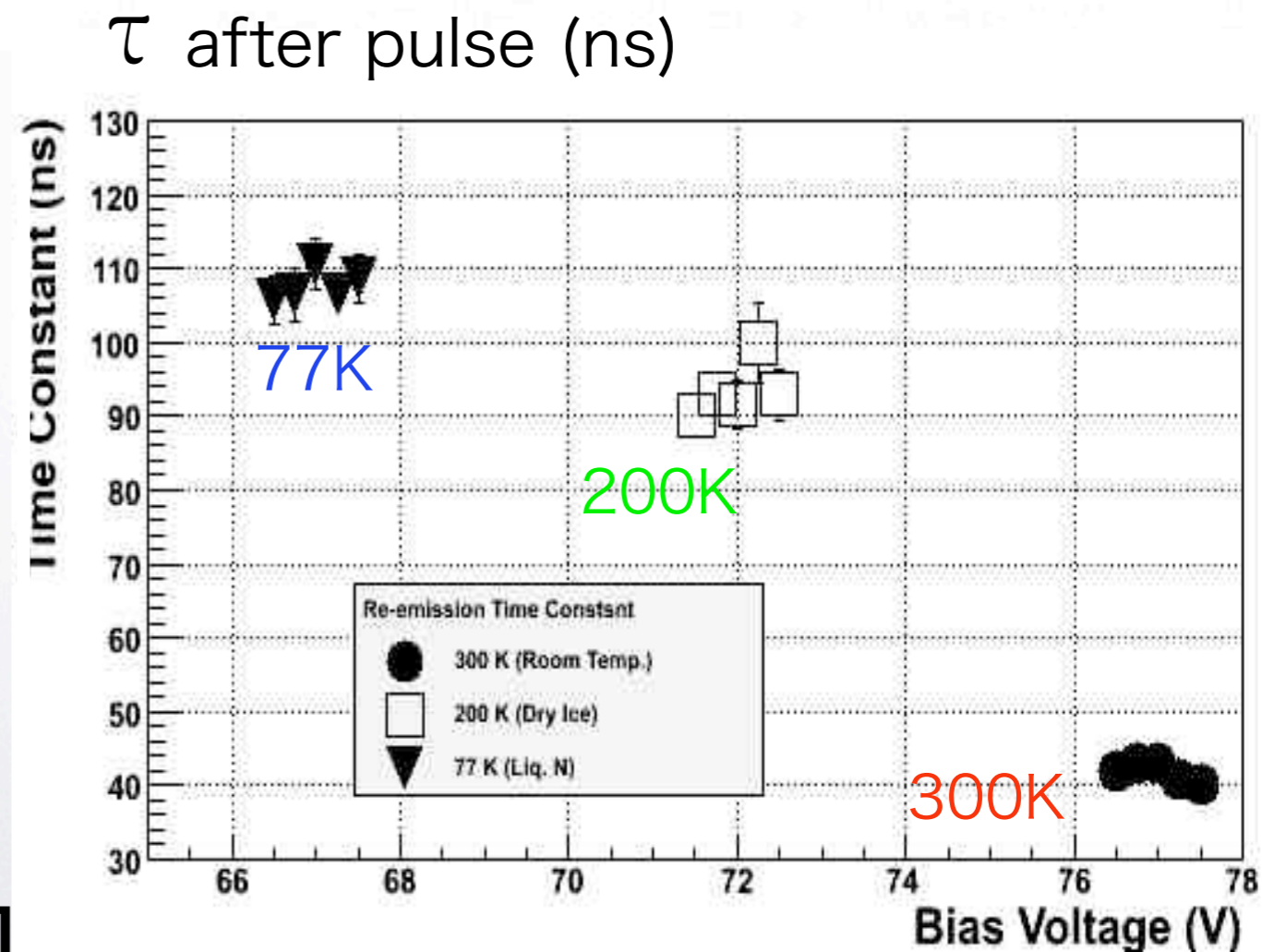
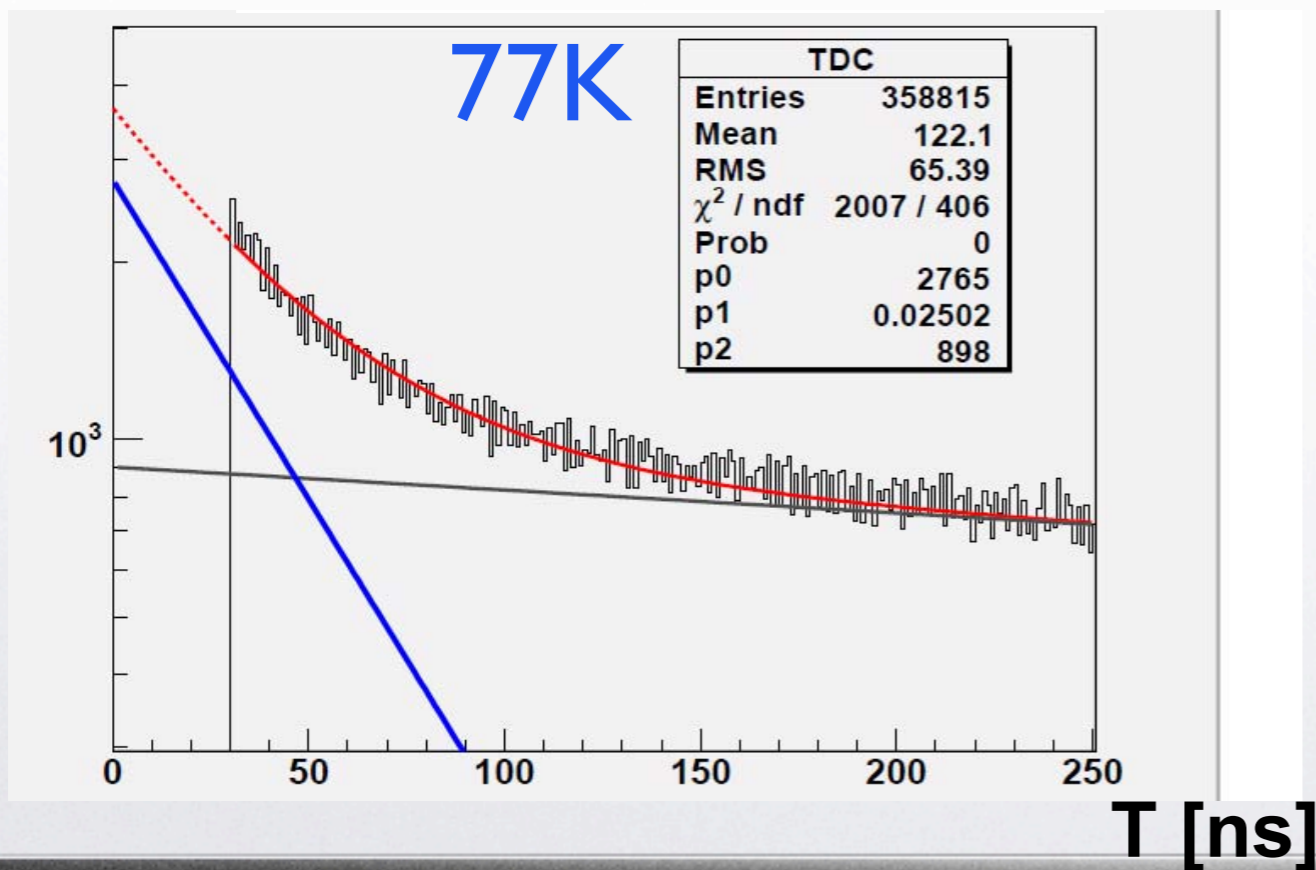


After pulses 3



- τ after pulse
- may depend on the temperature
- because of silicon nature

measured distribution

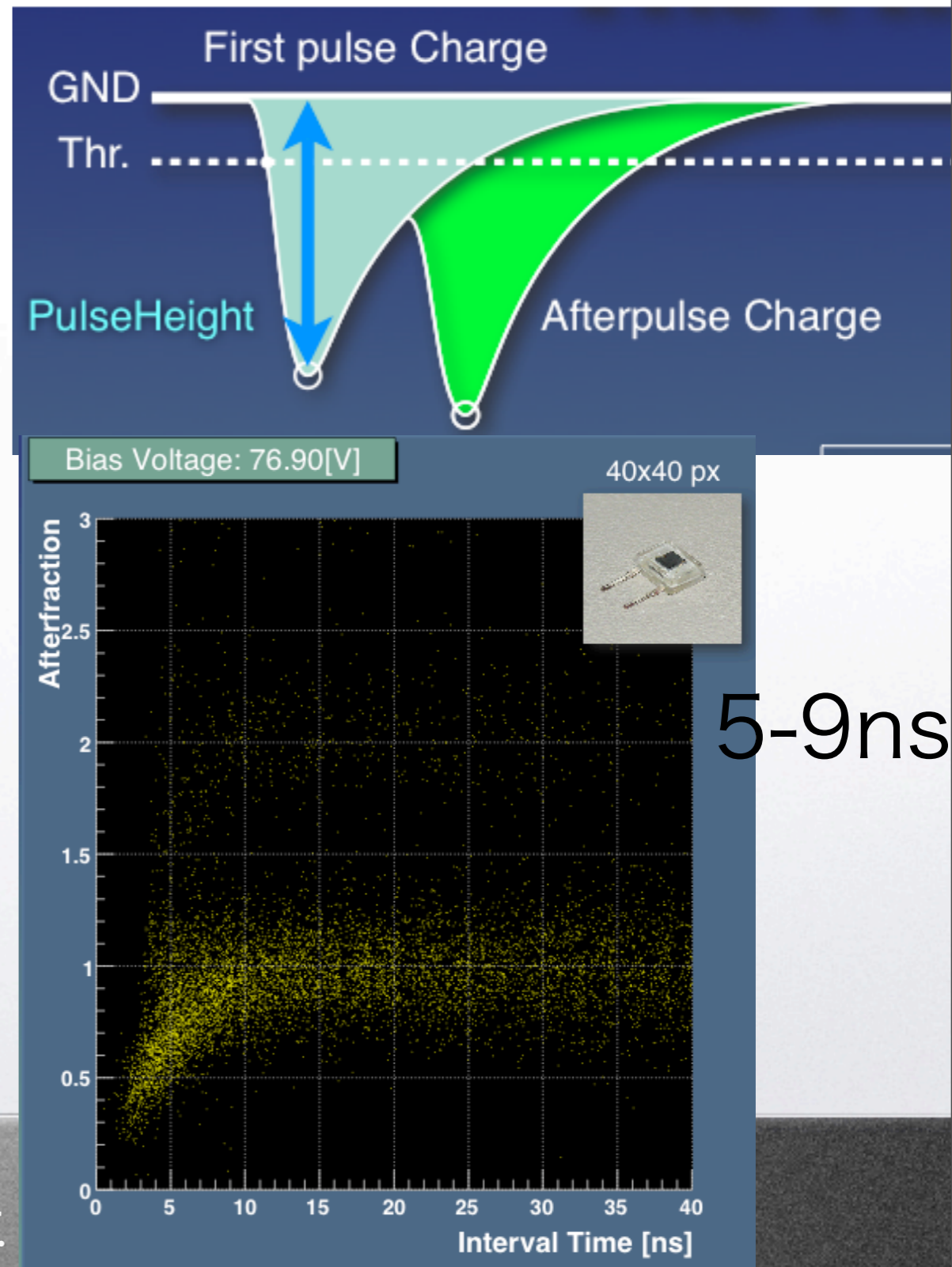
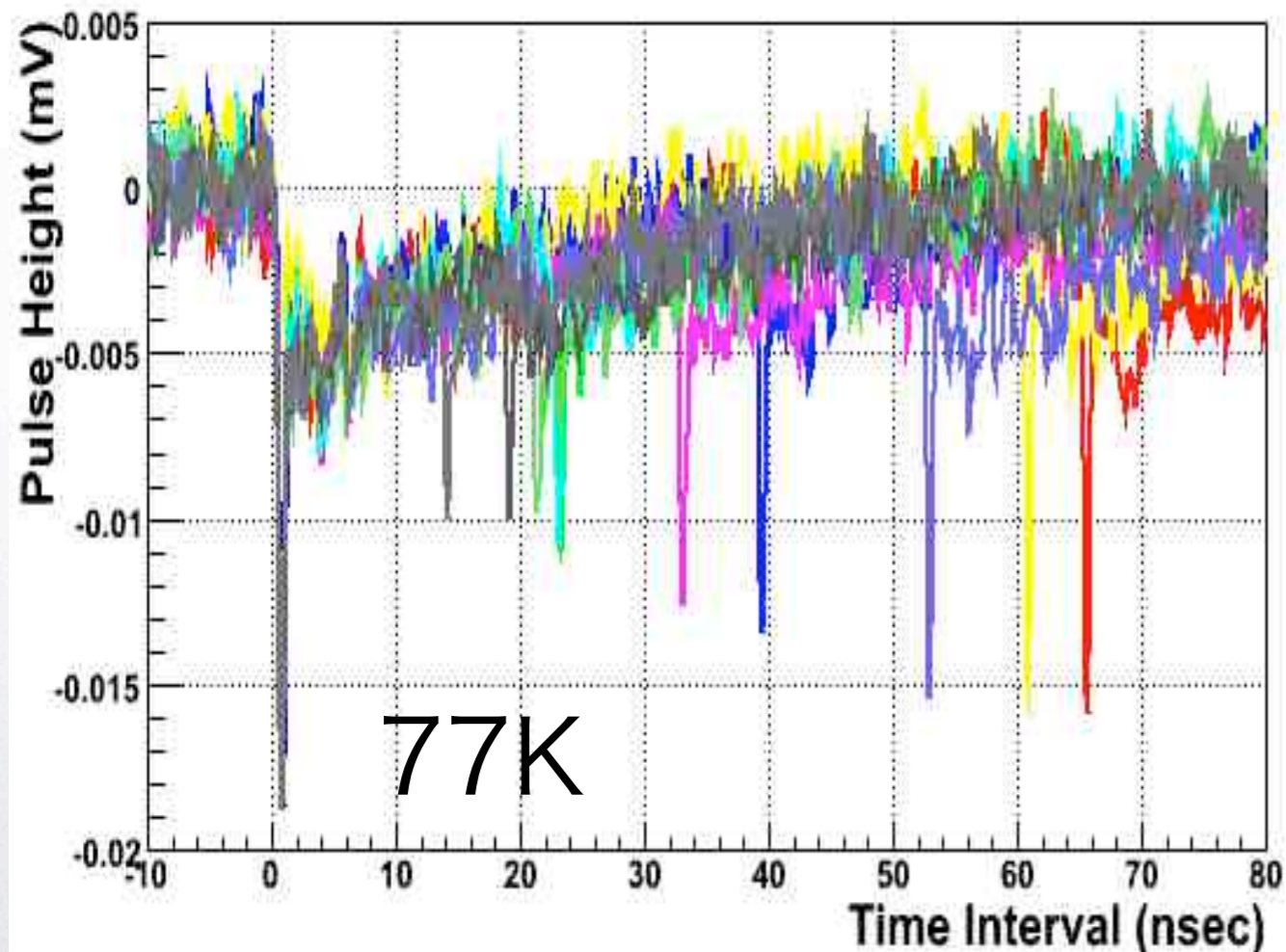




After pulses 4

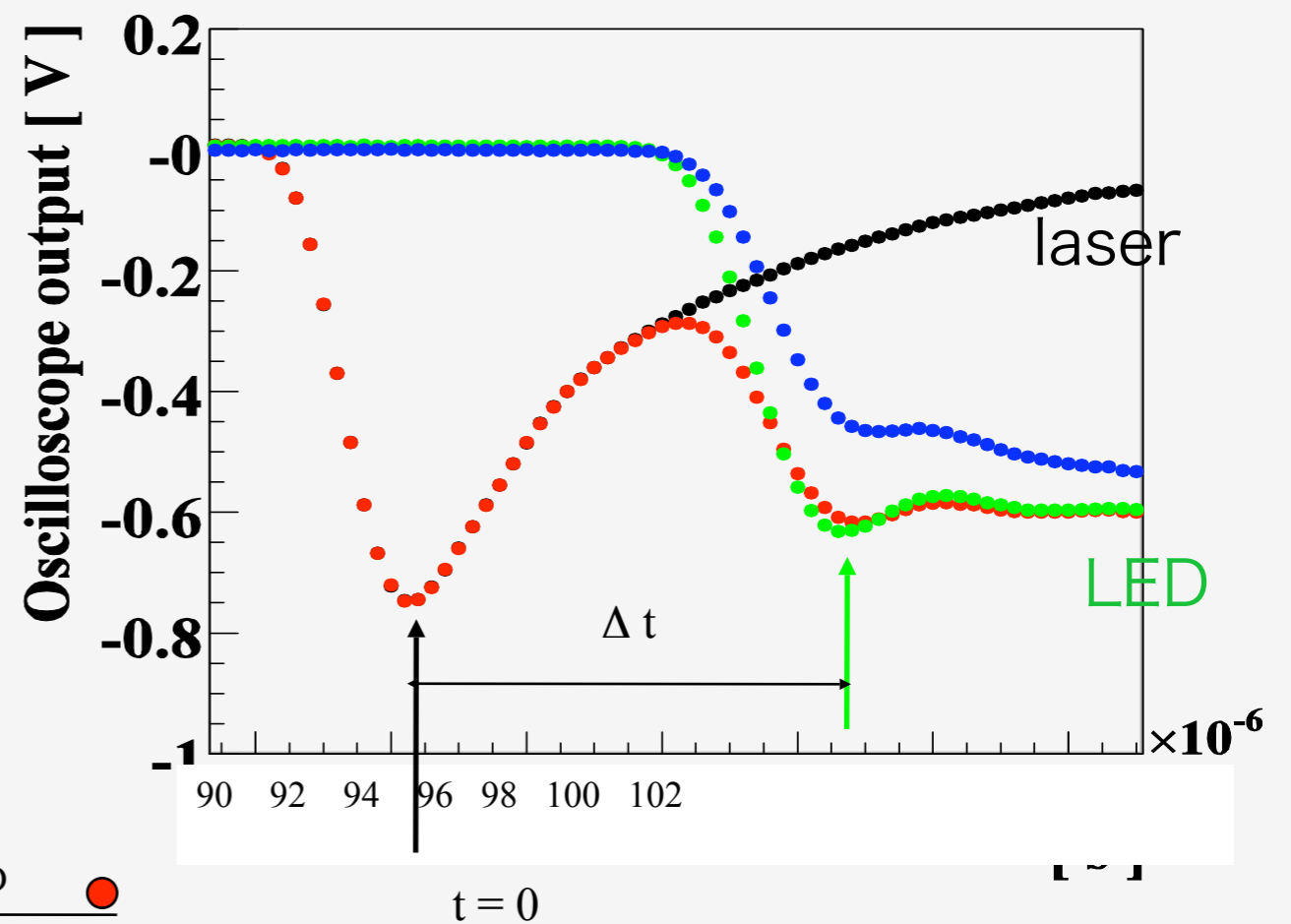
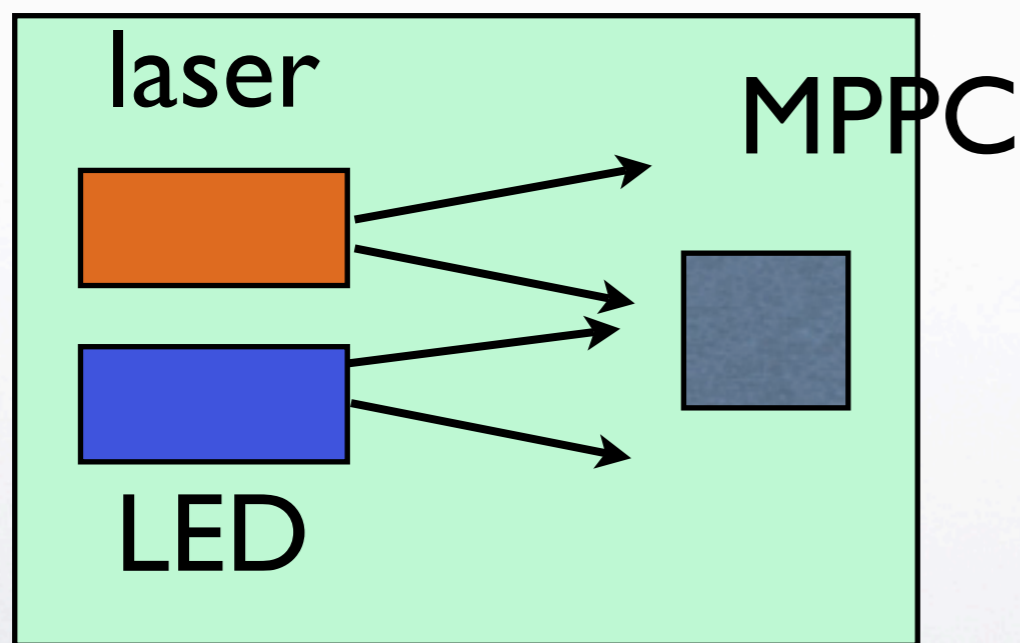
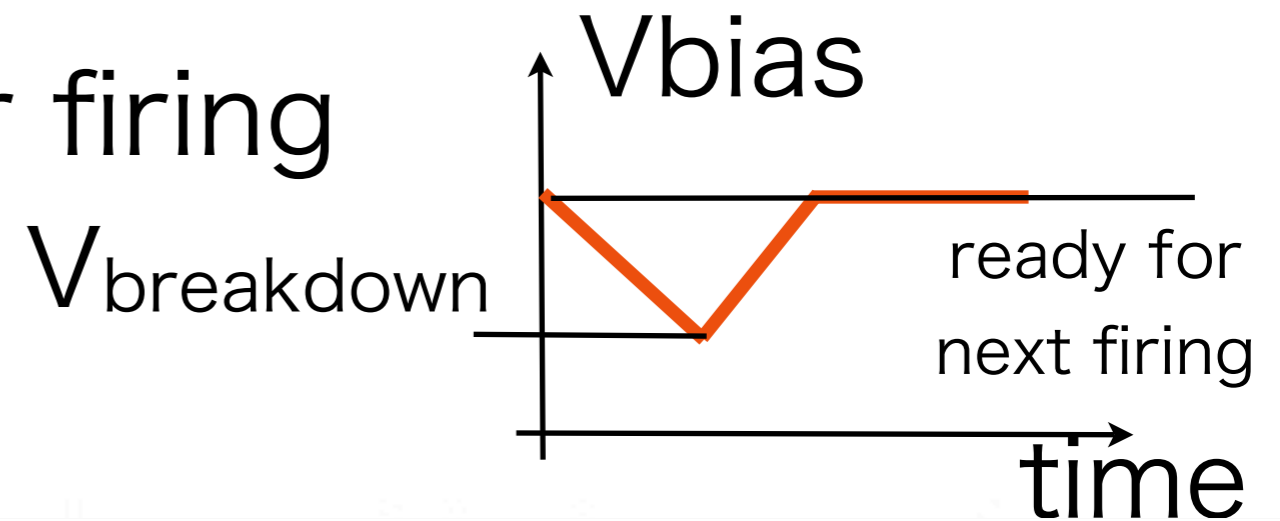


- recovering due to V_{bias} filling
- time const. dep. R_{quench}



Recovering

- V_{bias} decrease after firing
- recovering time
- measurements



- LASER ●
- LED ●
- LASER & LED ●
- LASER & LED - LASER ●



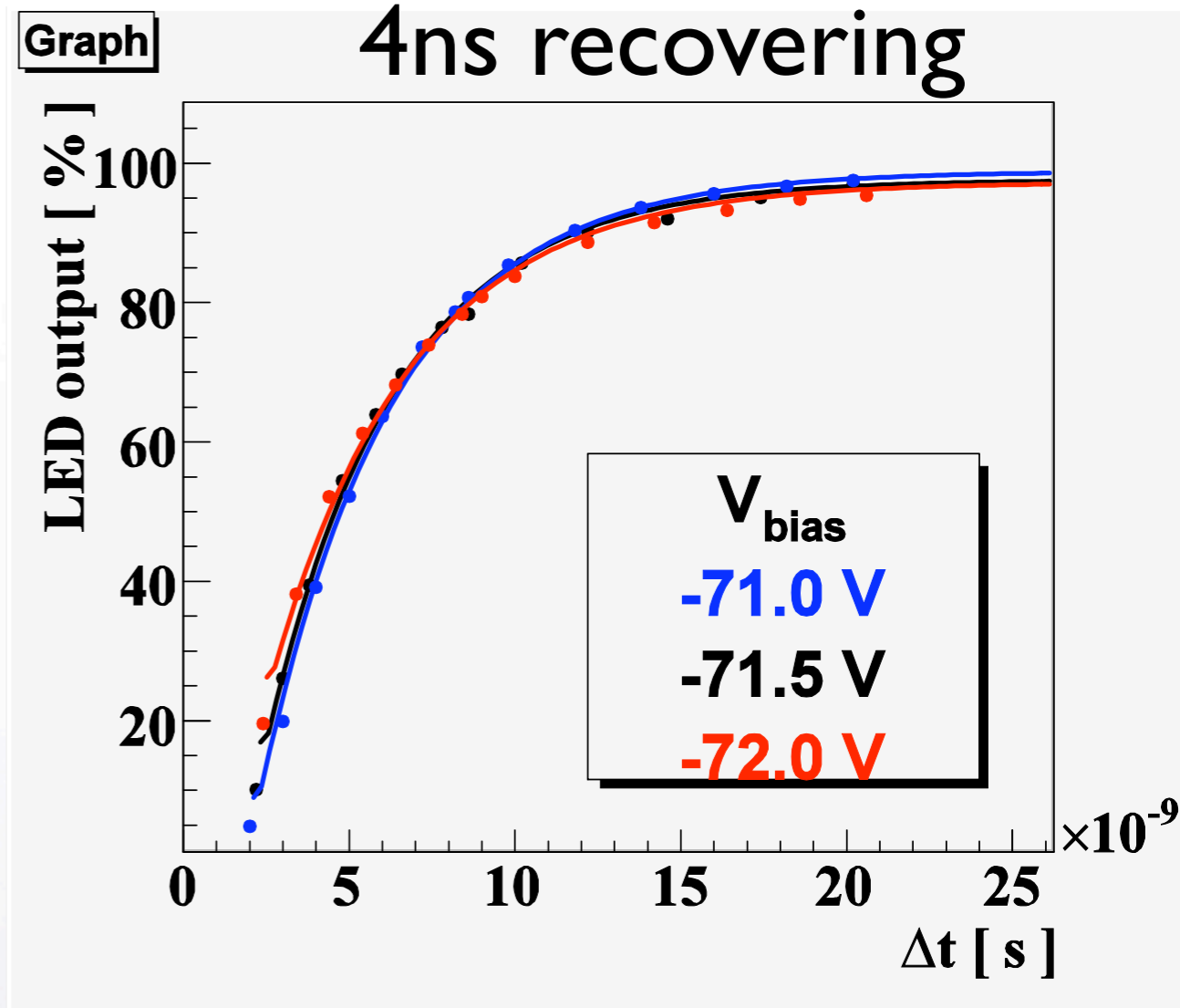
Recovering 2



- recovering fraction as a func. of time delay

$$\text{LED output} = \frac{(\text{LASER \& LED}) - \text{LASER}}{\text{LED}}$$

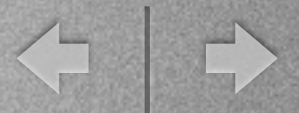
- indep. V_{bias}



This time is consistent with oscilloscope measurement



saturation effect.



- for big number of photons $> N_{\text{pixel}}$

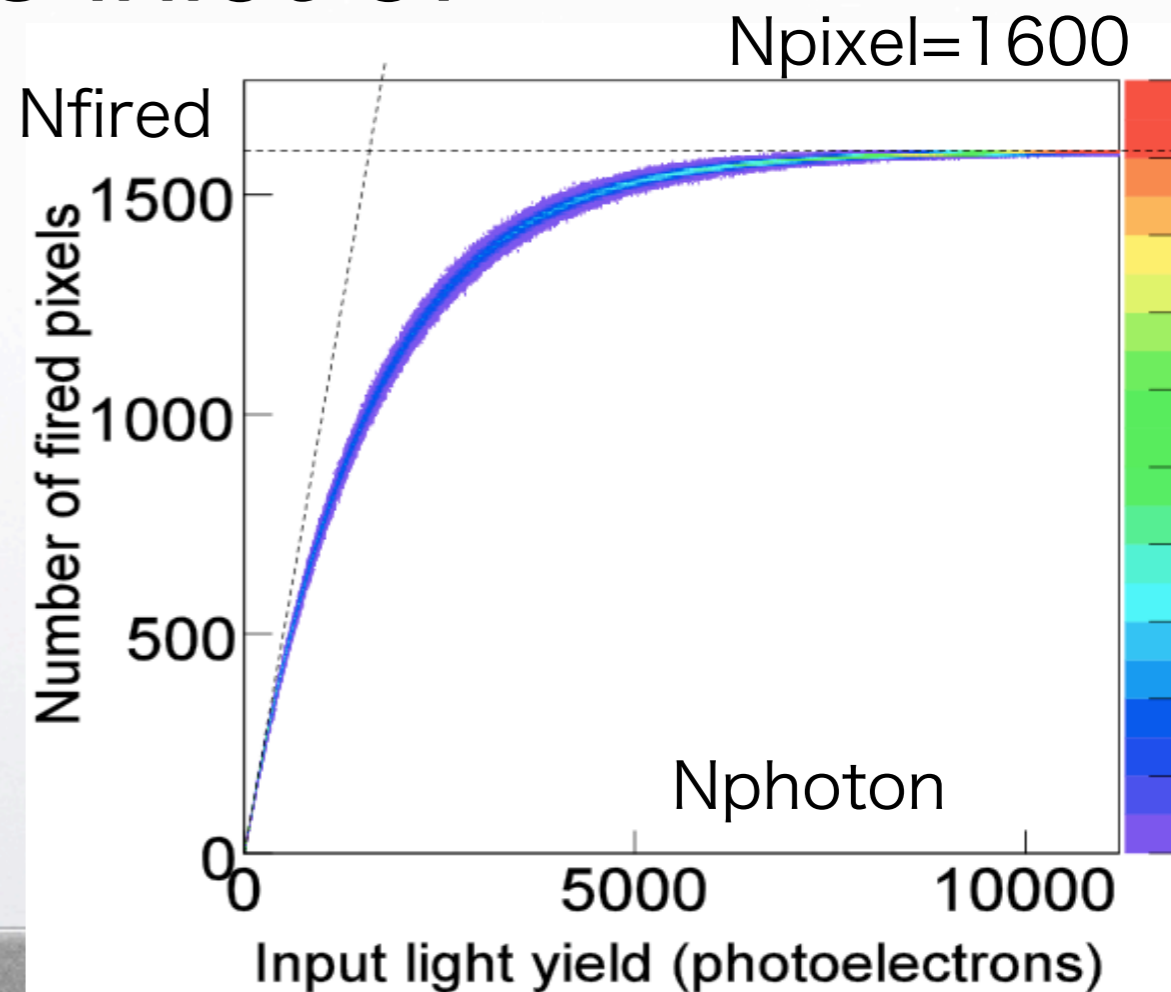
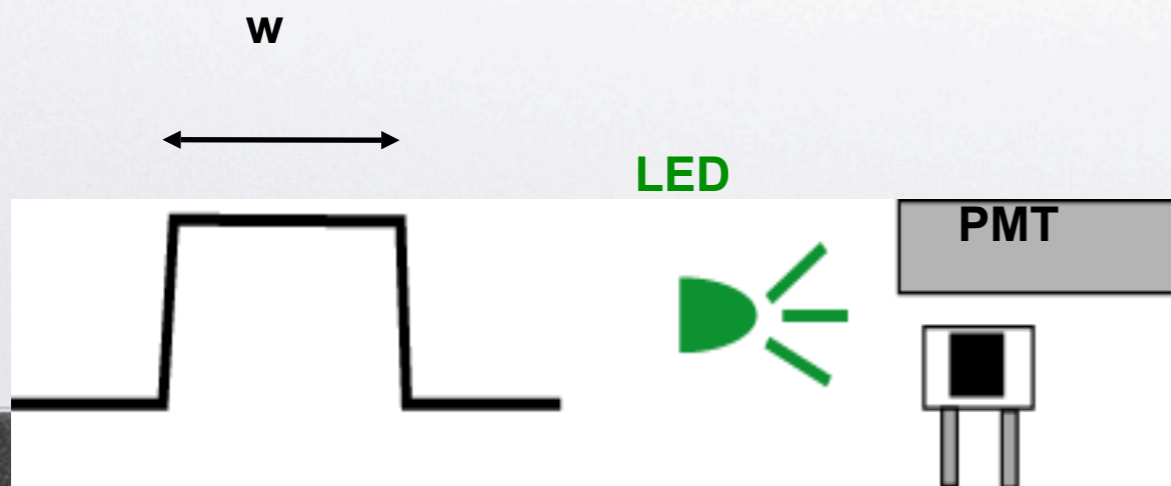
- in case of EM shower Max.

- output $\sim N_{\text{photon}}$ $N_{\text{fired}} = N_{\text{pixel}}(1 - e^{-\frac{N_{\text{photon}}}{N_{\text{pixel}}}})$

- ideal case (simultaneous inlet of photons)

- non linearity

- response curve



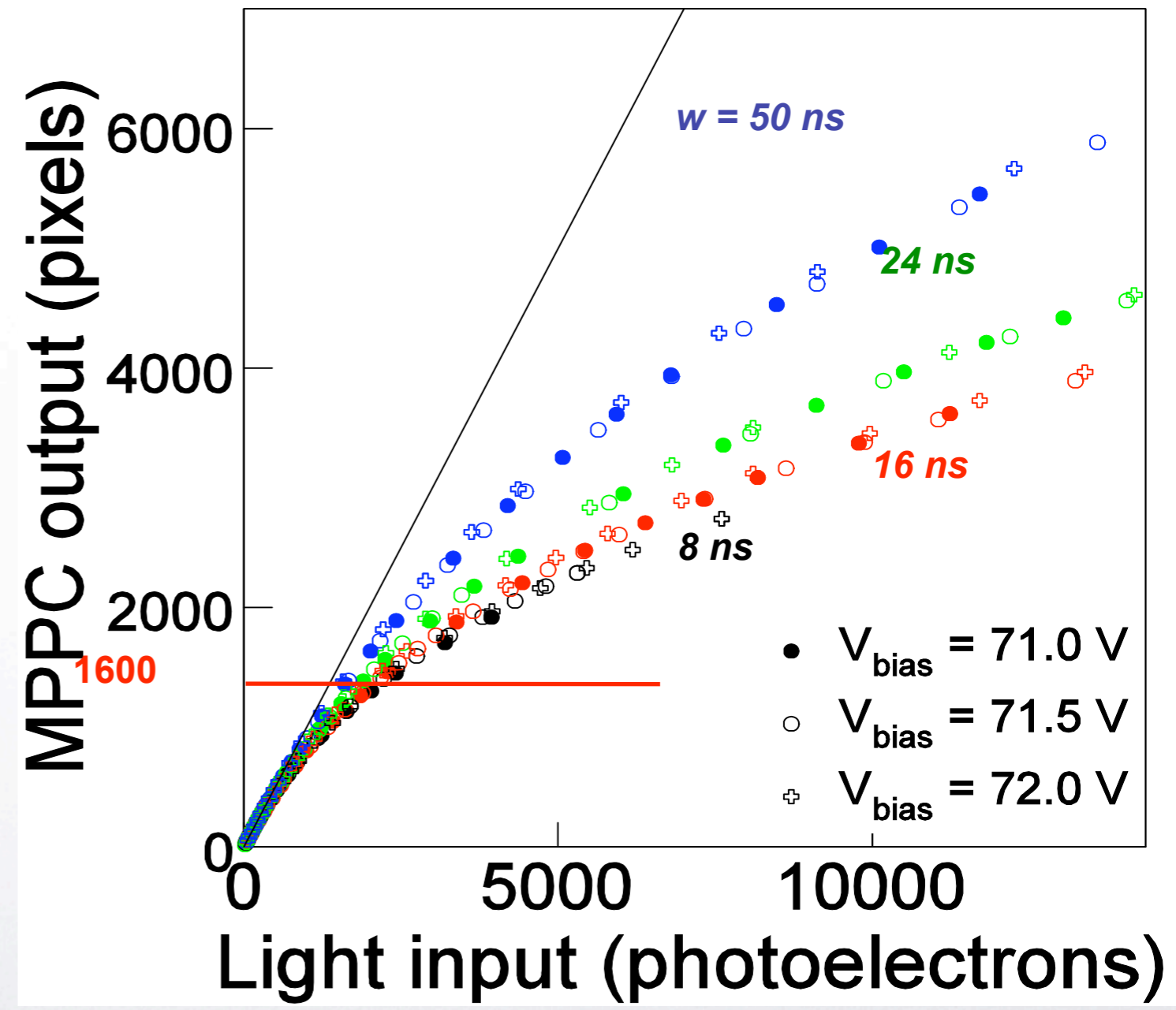


Saturation 2



- response curve
- up to 10000 photons
- dep. width

linear ~ 200p.e.

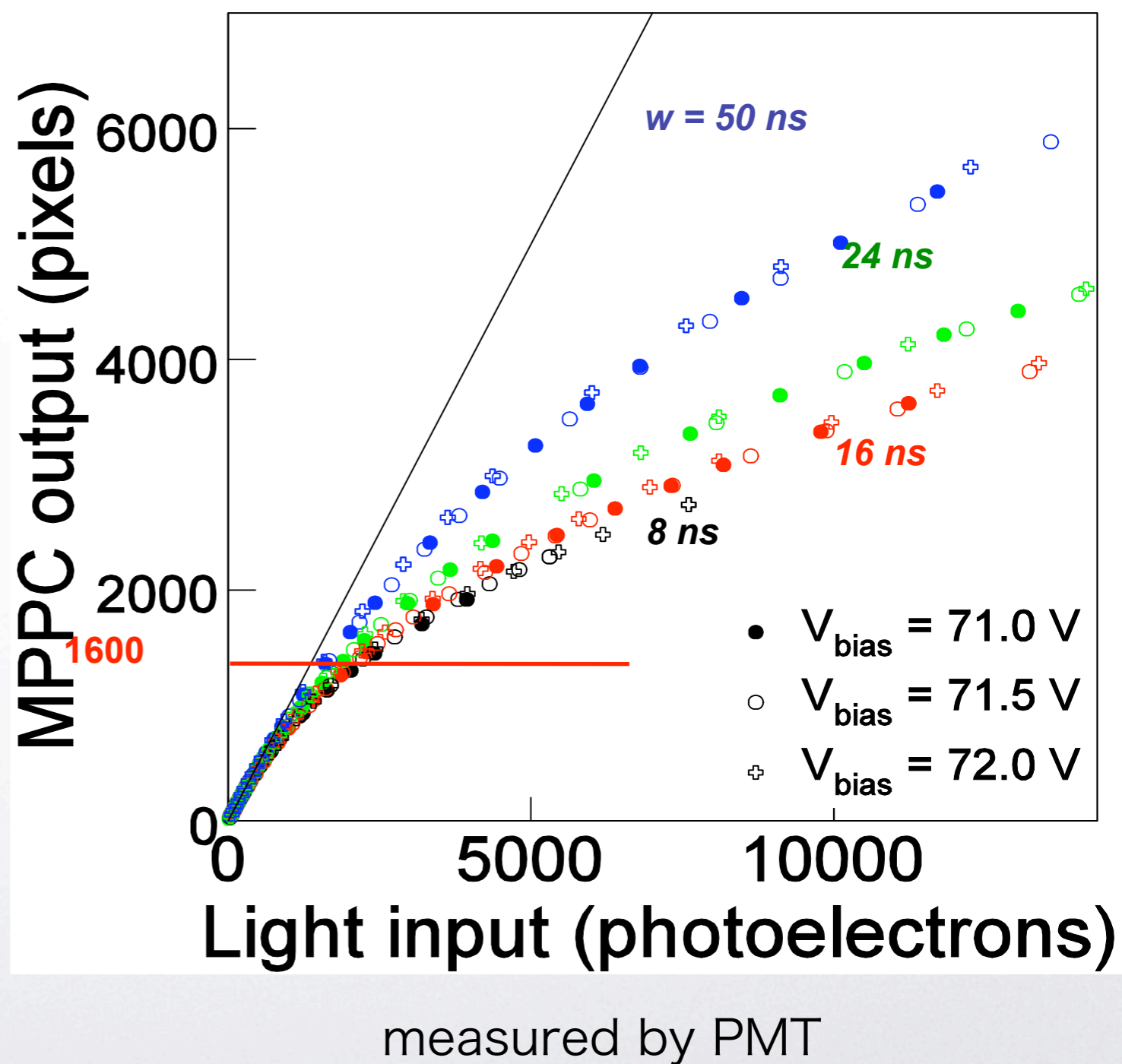
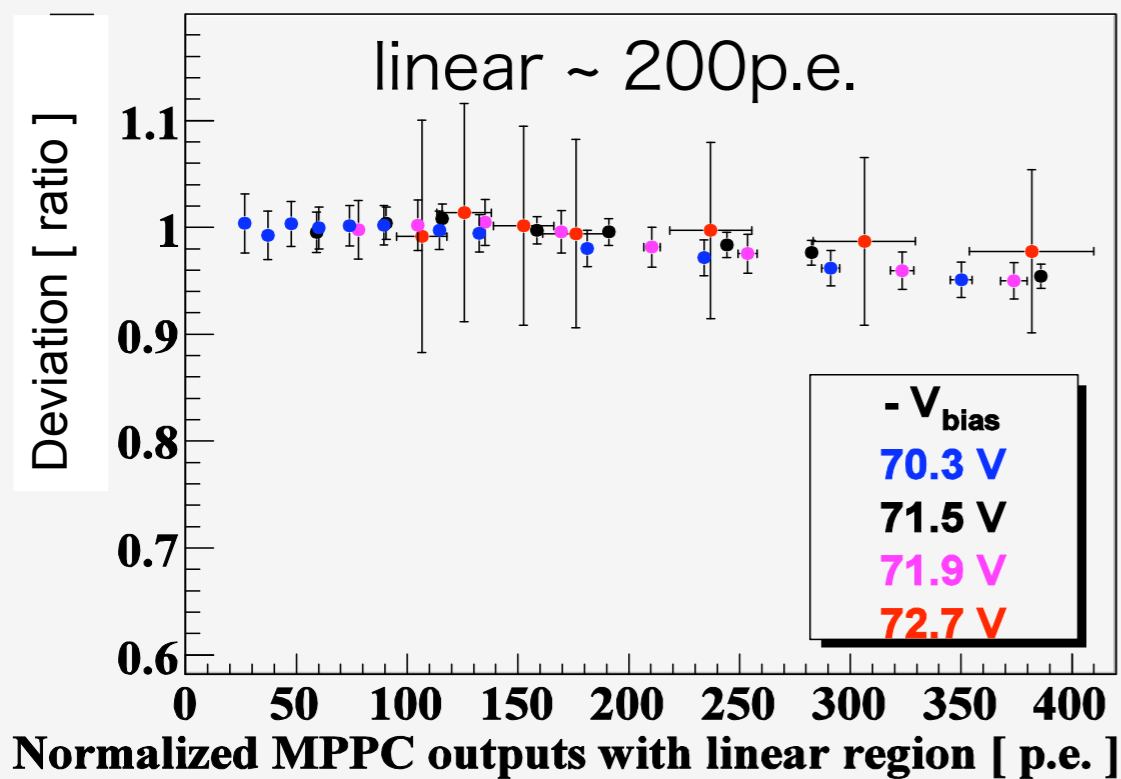




Saturation 2



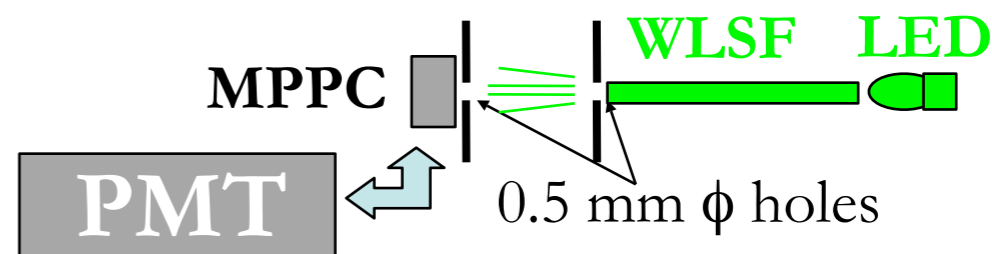
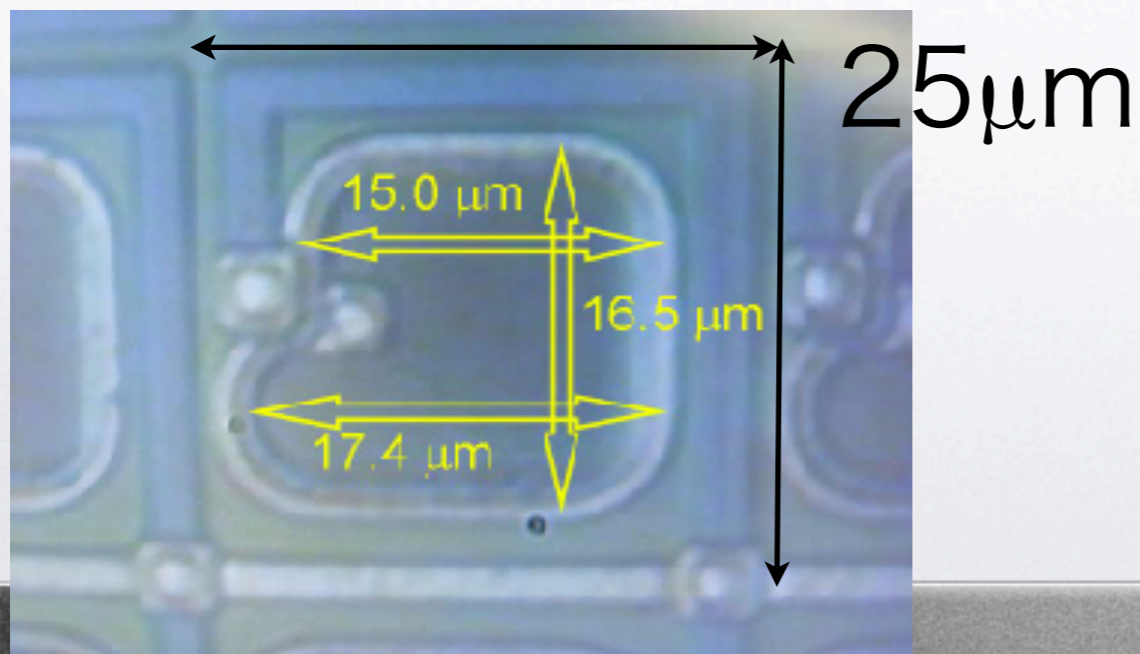
- response curve
- up to 10000 photons
- dep. width



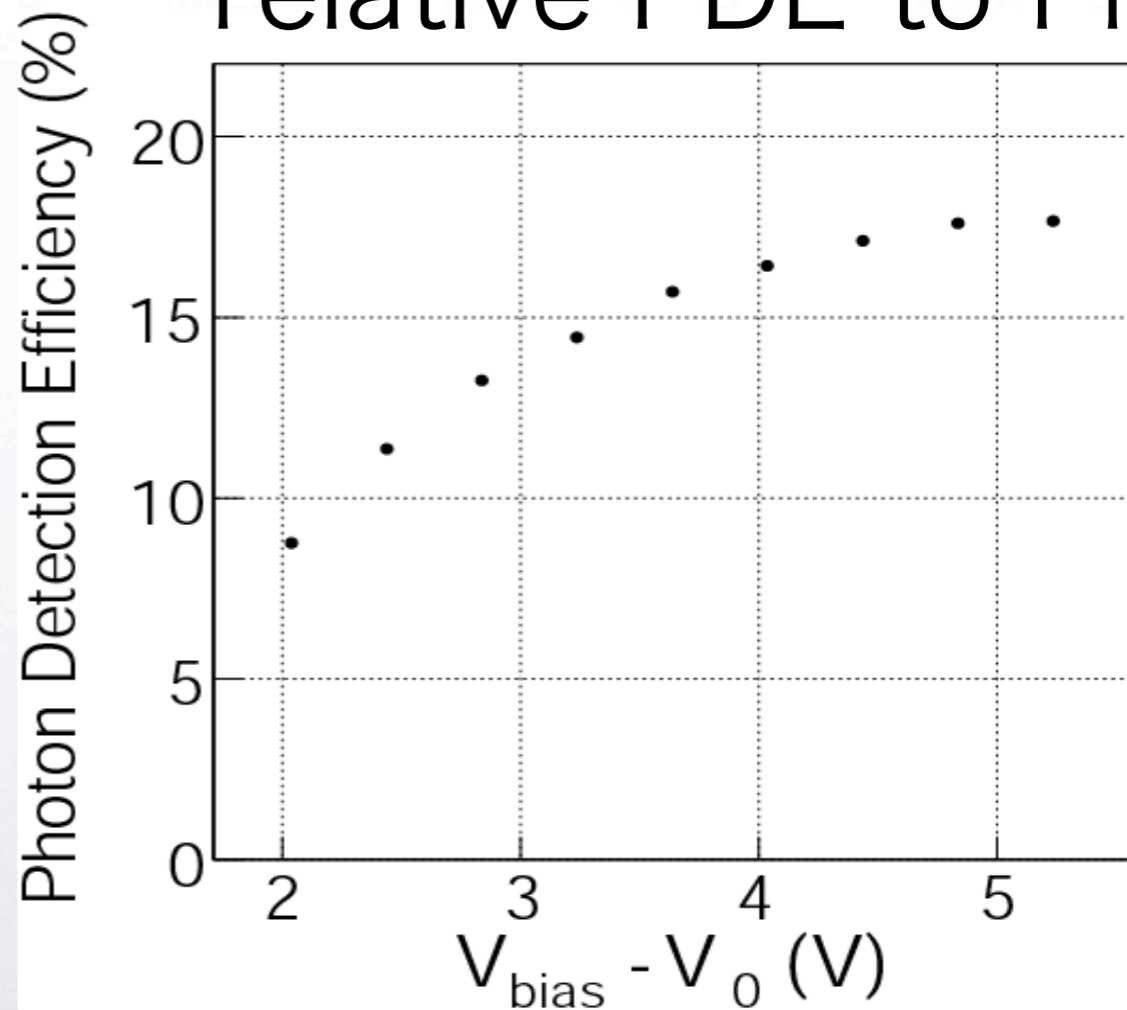
PDE

photon detection eff.

- $PDE(V_{bias}) = (QE(\lambda))$
• $(GM) \cdot (\text{window}) \sim 1$
• $1 \cdot 0.25 = 0.25 > QE$
(PMT)



relative PDE to PMT





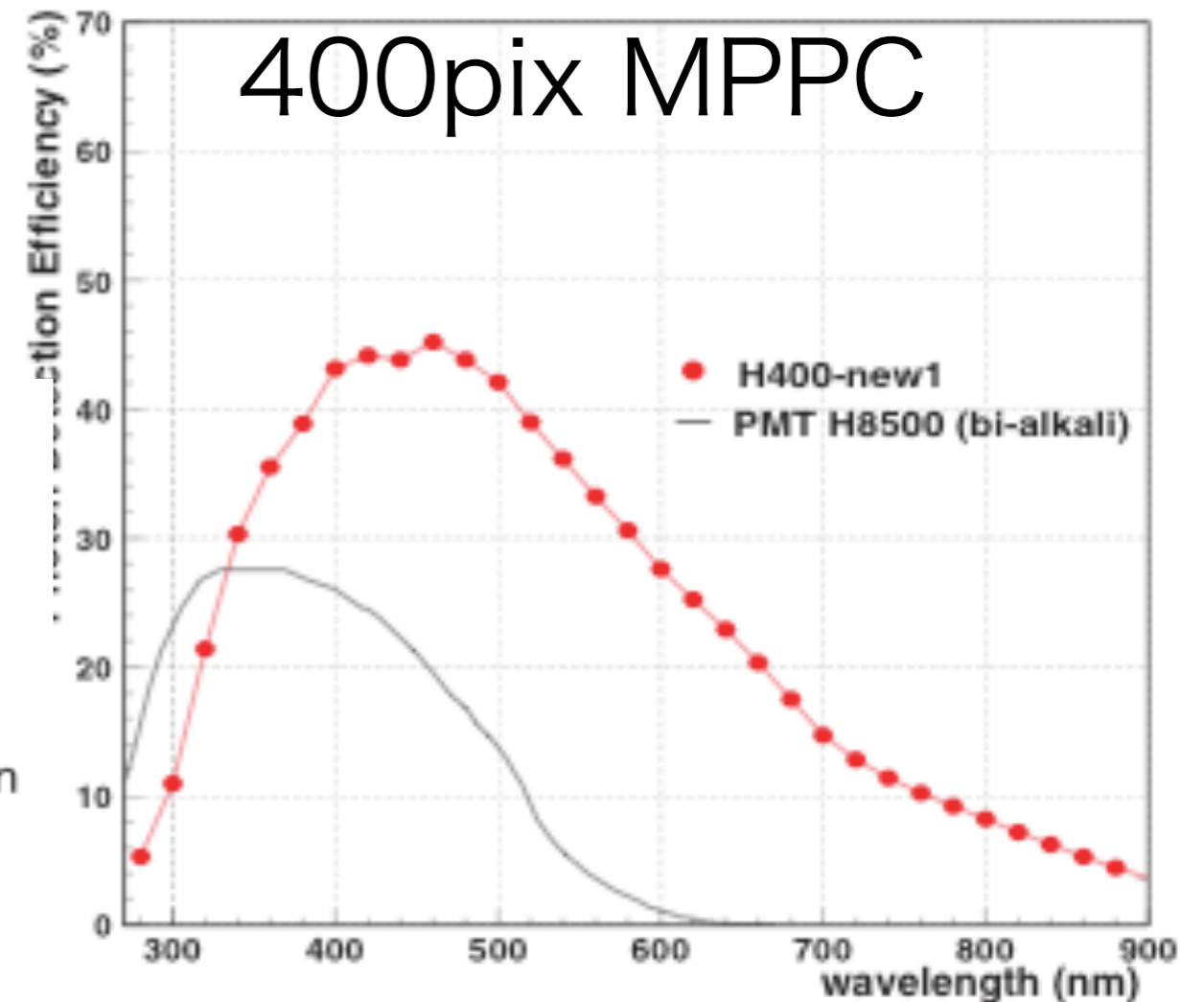
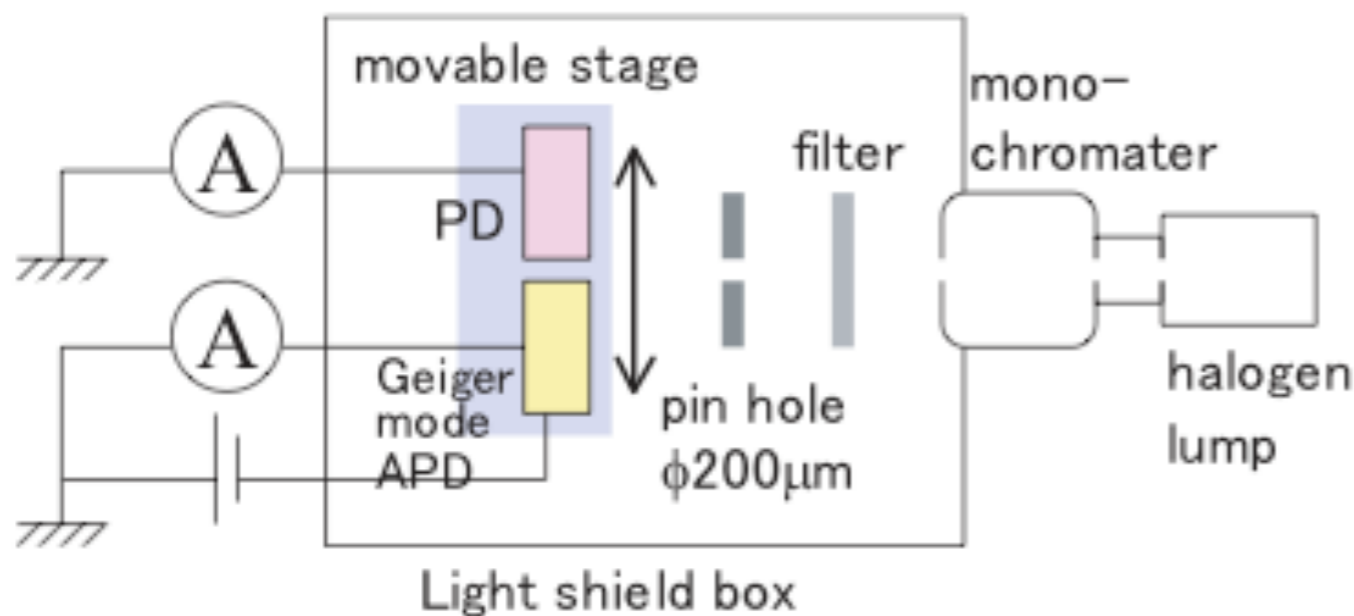
PDE 2



- PDE (b) wave length dep.
- blue sensitive
- good for scintillator

PDE including window si

400pix MPPC



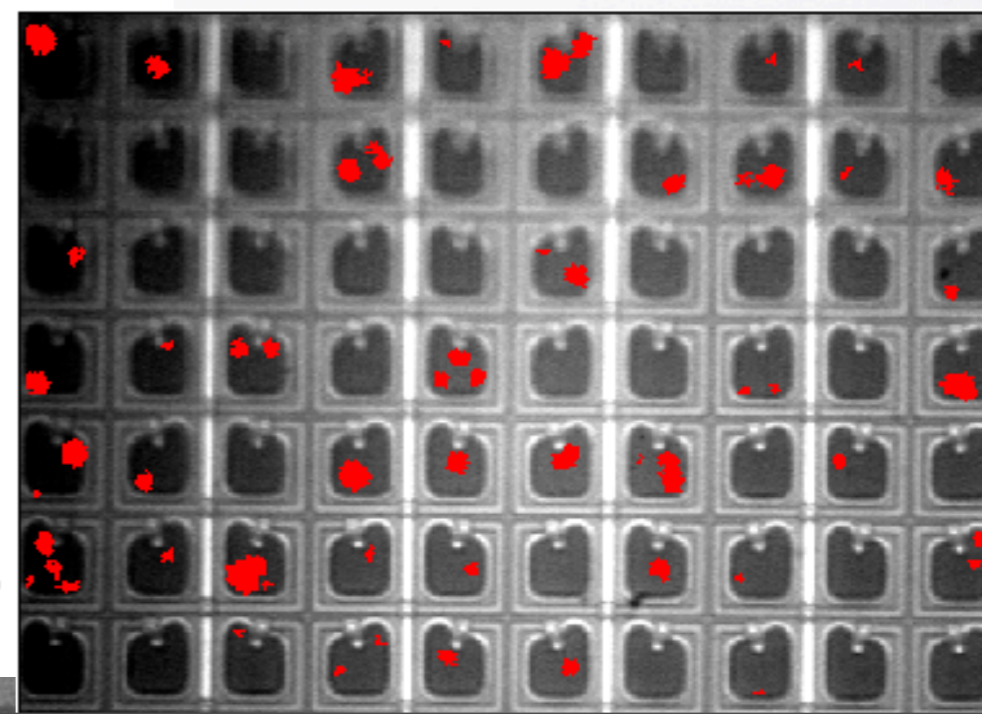
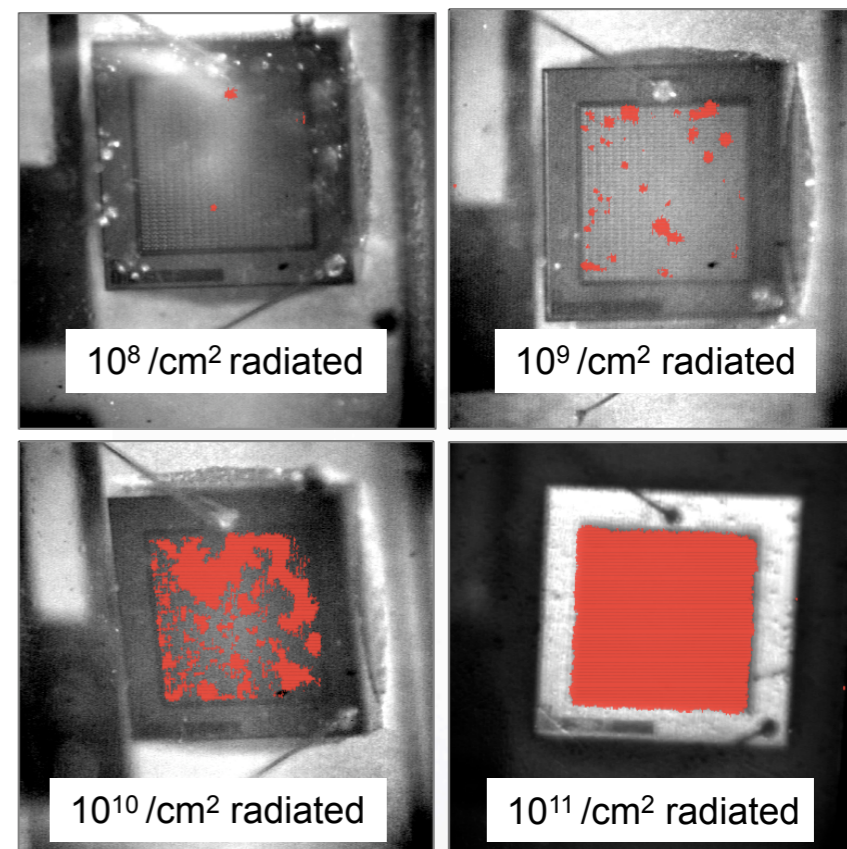
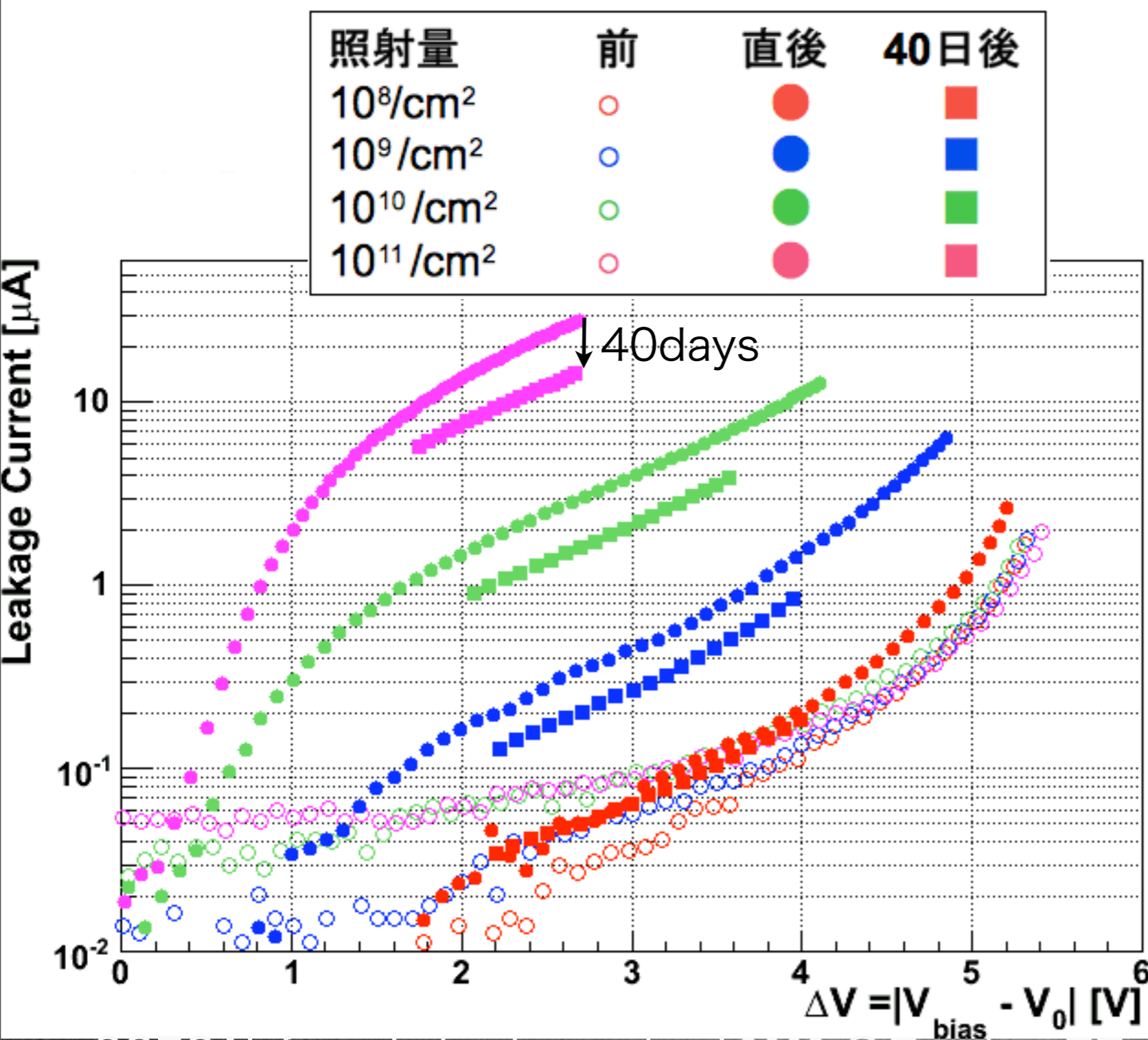
Mazuka



radiation tolerance ← | →

- neutron/ gamma tested

thermal cam.

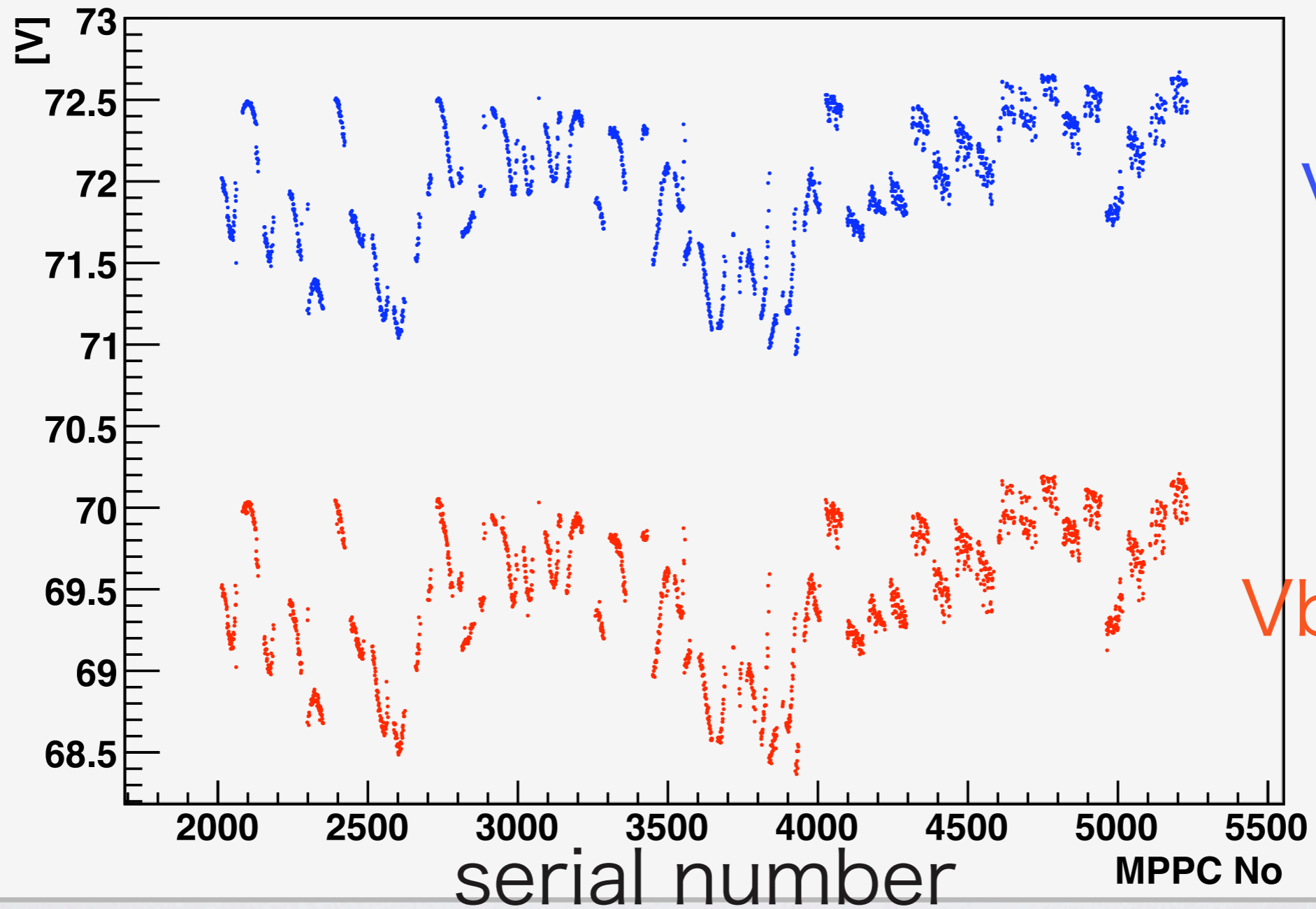




statistical experience

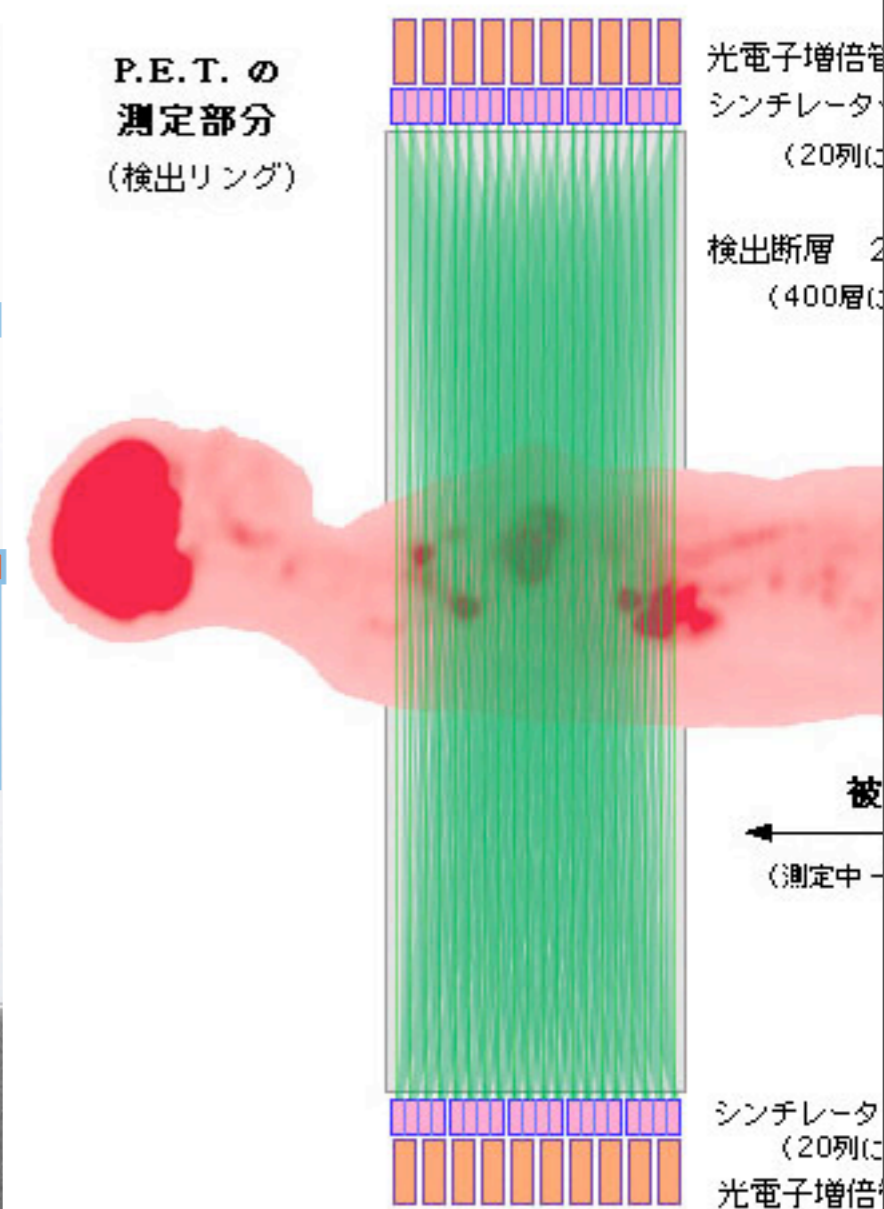
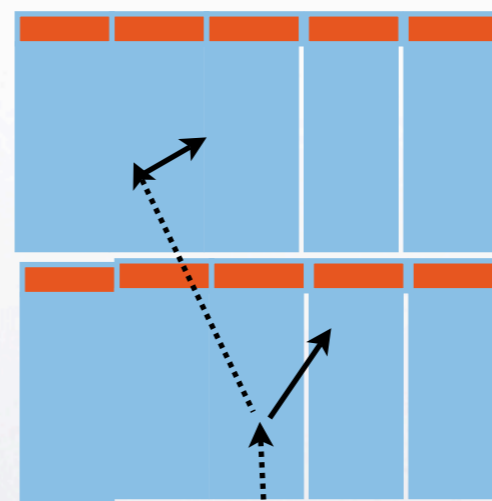
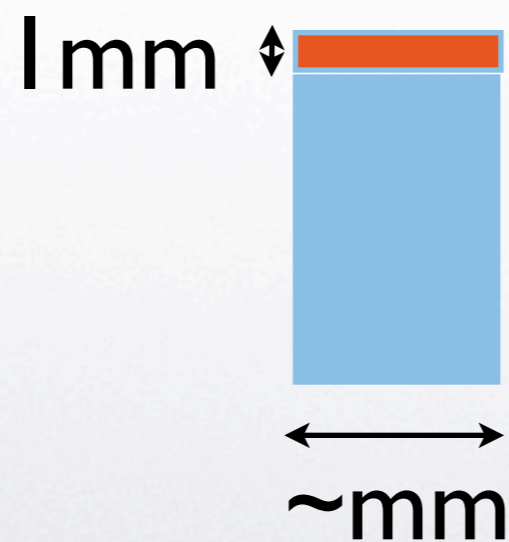
- we got 3000 pieces of MPPC

Graph



an application

- PET Positron Emission Tomography
- Cancer detection by $e^+e^- \rightarrow \gamma\gamma$, $E_\gamma = 0.511 \text{ MeV}$
- current resolution $\sim 10 \text{ mm}$
- close to 1 mm by smaller crystal
- & MPPC
- DOI





summary of MPPC

- R&D of MPPC is in progress
- good relation with HPK
- need more development
- more pixel
- less noise/cross talk
- improve after pulse shape